

Dual-Channel, 16-Bit, 800 MSPS, Digital-to-Analog Converter (DAC)

 Check for Samples: [DAC3283](#)

FEATURES

- Dual, 16-Bit, 800 MSPS DACs
- 8-Bit Input LVDS Data Bus
 - Byte-Wide Interleaved Data Load
 - 8 Sample Input FIFO
 - Optional Data Pattern Checker
- Multi-DAC Synchronization
- Selectable 2x-4x Interpolation Filters
 - Stop-Band Attenuation > 85 dB
- $F_s/2$ and $\pm F_s/4$ Coarse Mixer
- Digital Quadrature Modulator Correction
 - Gain, Phase and Offset Correction
- Temperature Sensor
- 3- or 4-Wire Serial Control Interface
- On-Chip 1.2-V Reference
- Differential Scalable Output: 2 to 20 mA
- Single-Carrier TM1 WCDMA ACLR: 82 dBc at $f_{OUT} = 122.88$ MHz
- Low Power: 1.3 W at 800 MSPS
- Space Saving Package: 48-pin 7x7mm QFN

APPLICATIONS

- Cellular Base Stations
- Diversity Transmit
- Wideband Communications
- Digital Synthesis

DESCRIPTION

The DAC3283 is a dual-channel 16-bit 800 MSPS digital-to-analog converter (DAC) with an 8-bit LVDS input data bus with on-chip termination, optional 2x-4x interpolation filters, digital IQ compensation and internal voltage reference. The DAC3283 offers superior linearity, noise and crosstalk performance.

Input data can be interpolated by 2x or 4x through on-chip interpolating FIR filters with over 85 dB of stop-band attenuation. Multiple DAC3283 devices can be fully synchronized.

The DAC3283 allows either a complex or real output. An optional coarse mixer in complex mode provides frequency upconversion and the dual DAC output produces a complex Hilbert Transform pair. The digital IQ compensation feature allows optimization of phase, gain and offset to maximize sideband rejection and minimize LO feed-through of an external quadrature modulator performing the final single sideband RF up-conversion.

The DAC3283 is characterized for operation over the entire industrial temperature range of -40°C to 85°C and is available in a 48-pin 7x7mm QFN package.

ORDERING INFORMATION

| T_A | ORDER CODE | PACKAGE DRAWING/TYPE ⁽¹⁾ ⁽²⁾ ⁽³⁾ | TRANSPORT MEDIA | QUANTITY |
|---|--------------|---|-----------------|----------|
| -40°C to 85°C | DAC3283IRGZT | RGZ/64QFN Quad Flatpack No-Lead | Tape and Reel | 250 |
| | DAC3283IRGZR | | | 2000 |

(1) Thermal Pad Size: 5,6 mm x 5,6 mm

(2) MSL Peak Temperature: Level-3-260C-168 HR

(3) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



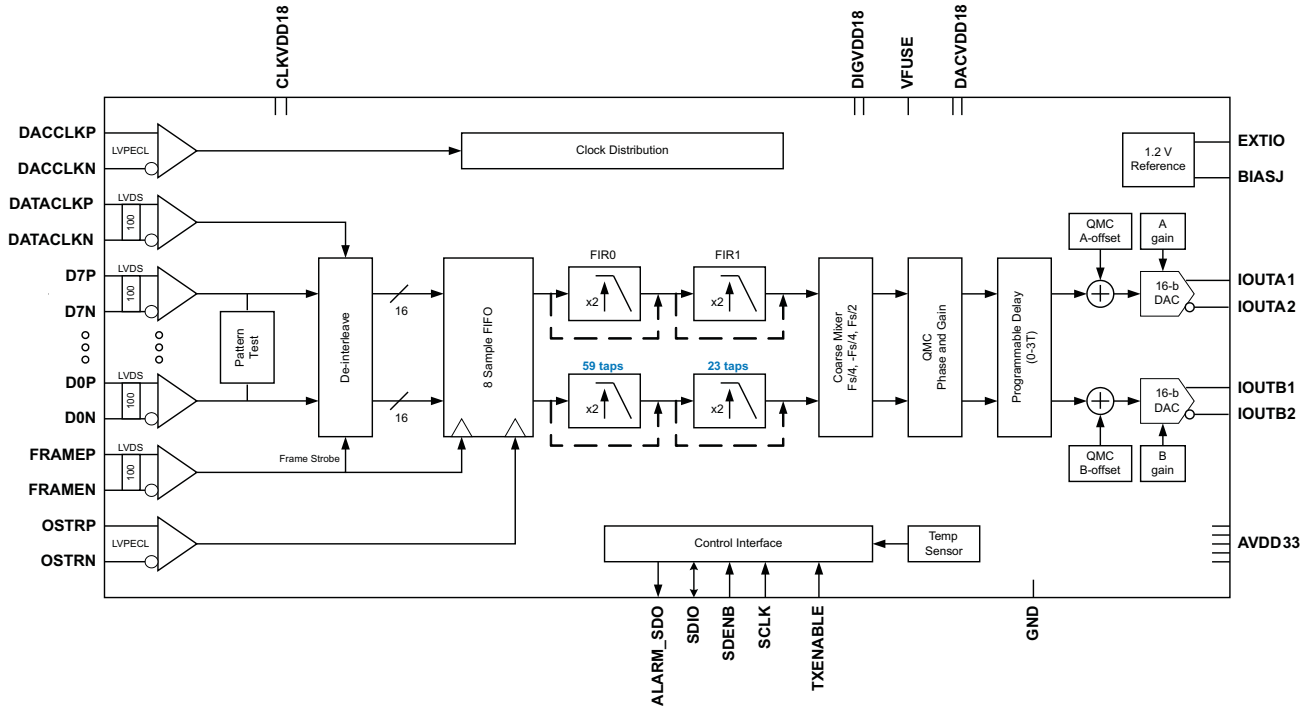
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

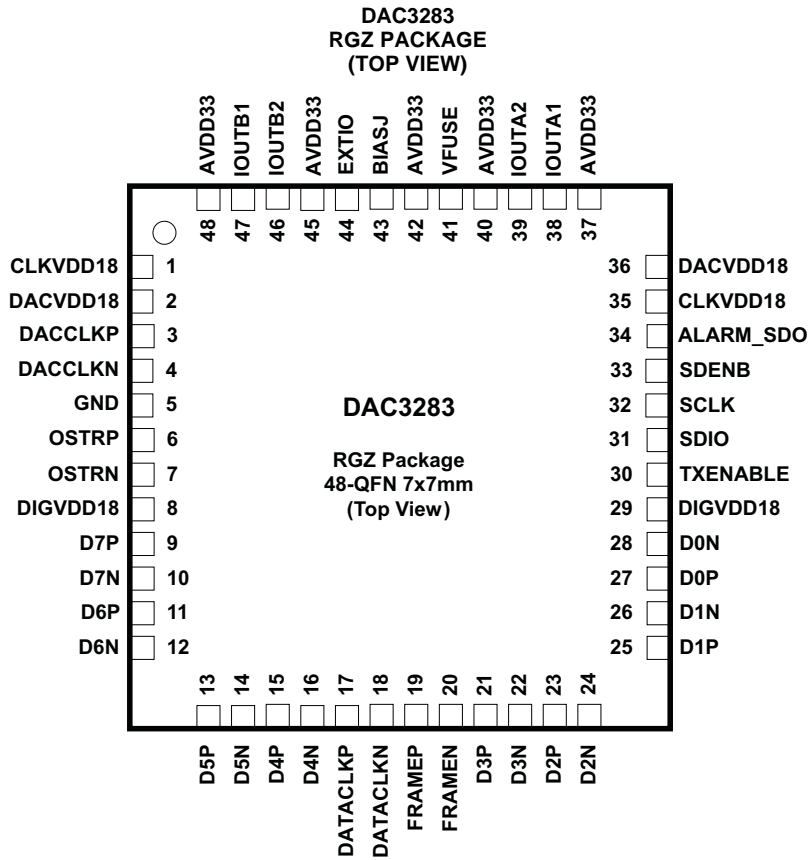


This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

FUNCTIONAL BLOCK DIAGRAM





TERMINAL FUNCTIONS

| TERMINAL | | I/O | DESCRIPTION |
|-----------|--------------------------------|-----|---|
| NAME | NO. | | |
| AVDD33 | 37, 40, 42, 45, 48 | I | Analog supply voltage. (3.3 V) |
| ALARM_SDO | 34 | O | 1.8V CMOS output for ALARM condition. The ALARM output functionality is defined through the CONFIG6 register. Default polarity is active low, but can be changed to active high via CONFIG0 alarm_pol control bit. Optionally, it can be used as the uni-directional data output in 4-pin serial interface mode (CONFIG 23 sif4_ena = '1'). |
| BIASJ | 43 | O | Full-scale output current bias. For 20mA full-scale output current, connect a 960Ω resistor to GND. |
| CLKVDD18 | 1, 35 | I | Internal clock buffer supply voltage. (1.8 V) It is recommended to isolate this supply from DACVDD18 and DIGVDD18. |
| D[7..0]P | 9, 11, 13, 15, 21, 23, 25, 27 | I | LVDS positive input data bits 0 through 7. Each positive/negative LVDS pair has an internal 100 Ω termination resistor. Data format relative to DATACLKP/N clock is Double Data Rate (DDR) with two data transfers per DATACLKP/N clock cycle. Dual channel 16-bit data is transferred byte-wide on this single 8-bit data bus using FRAMEP/N as a frame strobe indicator. D7P is most significant data bit (MSB) – pin 9 D0P is least significant data bit (LSB) – pin 27 The order of the bus can be reversed via CONFIG19 rev bit. |
| D[7..0]N | 10, 12, 14, 16, 22, 24, 26, 28 | I | LVDS negative input data bits 0 through 15. (See D[7:0]P description above) D7N is most significant data bit (MSB) – pin 10 D0N is least significant data bit (LSB) – pin 28 |
| DACCLKP | 3 | I | Positive external LVPECL clock input for DAC core with a self-bias of approximately CLKVDD18/2. |
| DACCLKN | 4 | I | Complementary external LVPECL clock input for DAC core. (see the DACCLKP description) |
| DACVDD18 | 2, 36 | I | DAC core supply voltage. (1.8 V) It is recommended to isolate this supply from CLKVDD18 and DIGVDD18. |

TERMINAL FUNCTIONS (continued)

| TERMINAL | | I/O | DESCRIPTION |
|----------|----------------|-----|---|
| NAME | NO. | | |
| DATACLKP | 17 | I | LVDS positive input data clock. This positive/negative pair has an internal 100 Ω termination resistor. Input data D[7:0]P/N is latched on both edges of DATACLKP/N (Double Data Rate) with two data transfers input per DATACLKP/N clock cycle. |
| DATACLKN | 18 | I | LVDS negative input data clock. (See DATACLKP description) |
| DIGVDD18 | 8, 29 | I | Digital supply voltage. (1.8V) It is recommended to isolate this supply from CLKVDD18 and DACVDD18. |
| EXTIO | 44 | I/O | Used as external reference input when internal reference is disabled through CONFIG25 extref_ena = '1'. Used as internal reference output when CONFIG25 extref_ena = '0' (default). Requires a 0.1 μ F decoupling capacitor to AGND when used as reference output. |
| FRAMEP | 19 | I | LVDS frame indicator positive input. This positive/negative pair has an internal 100 Ω termination resistor. This signal is captured with the rising edge of DATACLKP/N and used to indicate the beginning of the frame. It is also used as a reset signal by the FIFO. The FRAMEP/N signal should be edge-aligned with D[7:0]P/N. |
| FRAMEN | 20 | I | LVDS frame indicator negative input. (See the FRAMEN description) |
| GND | 5, Thermal Pad | I | Pin 5 and the Thermal Pad located on the bottom of the QFN package is ground for all supplies. |
| IOUTA1 | 38 | O | A-Channel DAC current output. An offset binary data pattern of 0x0000 at the DAC input results in a full scale current sink and the least positive voltage on the IOUTA1 pin. Similarly, a 0xFFFF data input results in a 0 mA current sink and the most positive voltage on the IOUTA1 pin. |
| IOUTA2 | 39 | O | A-Channel DAC complementary current output. The IOUTA2 has the opposite behavior of the IOUTA1 described above. An input data value of 0x0000 results in a 0 mA sink and the most positive voltage on the IOUTA2 pin. |
| IOUTB1 | 47 | O | B-Channel DAC current output. Refer to IOUTA1 description above. |
| IOUTB2 | 46 | O | B-Channel DAC complementary current output. Refer to IOUTA2 description above. |
| OSTRP | 6 | I | LVPECL output strobe positive input. This positive/negative pair is captured with the rising edge of DACCLKP/N. It is used to reset the clock dividers and for multiple DAC synchronization. If unused it can be left floating. |
| OSTRN | 7 | I | LVPECL output strobe negative input. (See the OSTRP description) |
| SCLK | 32 | I | 1.8V CMOS serial interface clock. Internal pull-down. |
| SDENB | 33 | I | 1.8V CMOS active low serial data enable, always an input to the DAC3283. Internal pull-up. |
| SDIO | 31 | I/O | 1.8V CMOS serial interface data. Bi-directional in 3-pin mode (default). In 4-pin interface mode, the SDIO pin is an input only. Internal pull-down. |
| TXENABLE | 30 | I | 1.8V CMOS active high input. TXENABLE must be high for the DATA to the DAC to be enabled. When TXENABLE is low, the digital logic section is forced to all 0, and any input data is ignored. Internal pull-down. |
| VFUSE | 41 | I | Digital supply voltage. (1.8V) This supply pin is also used for factory fuse programming. Connect to DACVDD18 pins for normal operation. |

ABSOLUTE MAXIMUM RATINGS

 over operating free-air temperature range (unless otherwise noted) ⁽¹⁾

| | | VALUE | UNIT |
|--|---|---------------------------|------|
| Supply voltage range | DACVDD18 ⁽²⁾ | –0.5 to 2.3 | V |
| | DIGVDD18 ⁽²⁾ | –0.5 to 2.3 | V |
| | CLKVDD18 ⁽²⁾ | –0.5 to 2.3 | V |
| | VFUSE ⁽²⁾ | –0.5 to 2.3 | V |
| | AVDD33 ⁽²⁾ | –0.5 to 4 | V |
| Terminal voltage range | CLKVDD18 to DIGVDD18 | –0.5 to 0.5 | V |
| | DACVDD18 TO DIGVDD18 | –0.5 to 0.5 | V |
| | D[7..0]P ,D[7..0]N, DATACLKP, DATACLKN, FRAMEP, FRAMEN ⁽²⁾ | –0.5 to DIGVDD18 + 0.5 | V |
| | DACCLKP, DACCLKN, OSTRP, OSTRN ⁽²⁾ | –0.5 to CLKVDD18 + 0.5 | V |
| | ALARM_SDO, SDIO, SCLK, SDENB, TXENABLE ⁽²⁾ | –0.5 to DIGCLKVDD18 + 0.5 | V |
| | IOUTA1/B1, IOUTA2/B2 ⁽²⁾ | –1.0 to AVDD33 + 0.5 | V |
| | EXTIO, BIASJ ⁽²⁾ | –0.5 to AVDD33 + 0.5 | V |
| Peak input current (any input) | | 20 | mA |
| Peak total input current (all inputs) | | –30 | mA |
| Operating free-air temperature range, T _A : DAC3283 | | –40 to 85 | °C |
| Storage temperature range | | –65 to 150 | °C |

(1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) Measured with respect to GND.

THERMAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

| THERMAL CONDUCTIVITY | | 48ld QFN | UNIT |
|----------------------|--|----------|------|
| T _J | Maximum junction temperature ⁽¹⁾ ⁽²⁾ | 125 | °C |
| θ _{JA} | Theta junction-to-ambient (still air) | 30 | °C/W |
| | Theta junction-to-ambient (150 lfm) | 24 | |
| θ _{JB} | Theta junction-to-board | 8 | °C/W |
| θ _{Jp} | Theta junction-to-pad | 1.3 | °C/W |

(1) Air flow or heat sinking reduces θ_{JA} and may be required for sustained operation at 85° under maximum operating conditions.

(2) It is strongly recommended to solder the device thermal pad to the board ground plane.

ELECTRICAL CHARACTERISTICS — DC SPECIFICATIONS⁽¹⁾

over operating free-air temperature range, nominal supplies, IOUTFS = 20 mA (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--|---|--|------------|------------|------|---------------|
| RESOLUTION | | | 16 | | | Bits |
| DC ACCURACY | | | | | | |
| DNL | Differential nonlinearity | 1 LSB = IOUTFS/2 ¹⁶ | ±2 | | | LSB |
| INL | Integral nonlinearity | | ±4 | | | |
| ANALOG OUTPUT | | | | | | |
| Coarse gain linearity | | | ±0.04 | | | LSB |
| Offset error | | Mid code offset | ±0.01 | | | %FSR |
| Gain error | | With external reference | ±2 | | | %FSR |
| | | With internal reference | ±2 | | | %FSR |
| Gain mismatch | | With internal reference | -2 | 2 | | %FSR |
| Minimum full scale output current | | Nominal full-scale current, IOUTFS = 16 x IBIAS current. | 2 | | | mA |
| Maximum full scale output current | | | 20 | | | mA |
| Output compliance range ⁽²⁾ | | IOUTFS = 20 mA | AVDD -0.5V | AVDD +0.5V | | V |
| Output resistance | | | 300 | | | kΩ |
| Output capacitance | | | 5 | | | pF |
| REFERENCE OUTPUT | | | | | | |
| V _{ref} | Reference output voltage | | 1.14 | 1.2 | 1.26 | V |
| | Reference output current ⁽³⁾ | | 100 | | | nA |
| REFERENCE INPUT | | | | | | |
| V _{EXTIO} | Input voltage range | External reference mode | 0.1 | 1.2 | 1.25 | V |
| | Input resistance | | 1 | | | MΩ |
| | Small signal bandwidth | | 472 | | | kHz |
| | Input capacitance | | 100 | | | pF |
| TEMPERATURE COEFFICIENTS | | | | | | |
| Offset drift | | With external reference | ±1 | | | ppm of FSR/°C |
| Gain drift | | With internal reference | ±15 | | | ppm of FSR/°C |
| | | | ±30 | | | |
| Reference voltage drift | | | ±8 | | | ppm/°C |
| POWER SUPPLY | | | | | | |
| AVDD33 | | | 3.0 | 3.3 | 3.6 | V |
| DACVDD18, DIGVDD18, CLKVDD18 | | | 1.7 | 1.8 | 1.9 | V |
| I _(AVDD33) | Analog supply current | Mode 1 (below) | 149 | | | mA |
| I _(DIGVDD) | Digital supply current | | 340 | | | mA |
| I _(DACVDD18) | DAC supply current | | 55 | | | mA |
| I _(CLKVDD18) | Clock supply current | | 37 | | | mA |
| P | Power dissipation | Mode 1: f _{DAC} = 800MSPS, 4x interpolation, Fs/4 mixer on, QMC on | 1300 | | 1450 | mW |
| | | Mode 2: f _{DAC} = 491.52MSPS, 2x interpolation, Mixer off, QMC on | 1000 | | | mW |
| | | Mode 3: Sleep mode f _{DAC} = 800MSPS, 4x interpolation, Fs/4 mixer on, CONFIG24 sleepa , sleepb set = 1 | 750 | | | mW |
| | | Mode 4: Power-Down mode No clock, static data pattern, CONFIG23 clkpath_sleep_a , clkpath_sleepb set = 1 CONFIG24 clkrecv_sleep , sleepa , sleepb set = 1 | 7 | 18 | | mW |
| PSRR | Power supply rejection ratio | DC tested | ±0.2 | | | %FSR/V |
| T | Operating range | | -40 | 25 | 85 | °C |

(1) Measured differential across IOUTA1 and IOUTA2 with 25 Ω each to AVDD.

(2) The lower limit of the output compliance is determined by the CMOS process. Exceeding this limit may result in transistor breakdown, resulting in reduced reliability of the DAC3283 device. The upper limit of the output compliance is determined by the load resistors and full-scale output current. Exceeding the upper limit adversely affects distortion performance and integral nonlinearity.

(3) Use an external buffer amplifier with high impedance input to drive any external load.

ELECTRICAL CHARACTERISTICS — AC SPECIFICATIONS

Over recommended operating free-air temperature range, nominal supplies, IOUTFS = 20 mA (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------------------------|--|--|-----|-------|-----|------------------|
| ANALOG OUTPUT⁽¹⁾ | | | | | | |
| f _{DAC} | Maximum DAC output update rate | 1x Interpolation | | 312.5 | | MSPS |
| | | 2x Interpolation | | 625 | | |
| | | 4x Interpolation | | 800 | | |
| t _{s(DAC)} | Output settling time to 0.1% | Transition: Code 0x0000 to 0xFFFF | | 10.4 | | ns |
| t _{pd} | Output propagation delay | DAC outputs are updated on the falling edge of DAC clock. Does not include digital latency (see below). | | 2 | | ns |
| t _{r(IOUT)} | Output rise time 10% to 90% | | | 220 | | ps |
| t _{f(IOUT)} | Output fall time 90% to 10% | | | 220 | | ps |
| Power-up time | DAC wake-up time | IOUT current settling to 1% of IOUTFS. Measured from SDENB rising edge; Register CONFIG24, toggle sleepa from 1 to 0. | | 90 | | μs |
| | DAC sleep time | IOUT current settling to less than 1% of IOUTFS. Measured from SDENB rising edge; Register CONFIG24, toggle sleepa from 0 to 1. | | 90 | | |
| Digital latency | | 1x Interpolation | | 59 | | DAC clock cycles |
| | | 2x Interpolation | | 139 | | |
| | | 4x Interpolation | | 290 | | |
| | | QMC | | 24 | | |
| AC PERFORMANCE⁽²⁾ | | | | | | |
| SFDR | Spurious free dynamic range (0 to f _{DAC} /2)Tone at 0 dBFS | f _{DAC} = 800 MSPS, f _{OUT} = 20.1 MHz | | 85 | | dBc |
| | | f _{DAC} = 800 MSPS, f _{OUT} = 50.1 MHz | | 76 | | |
| | | f _{DAC} = 800 MSPS, f _{OUT} = 70.1 MHz | | 72 | | |
| IMD3 | Third-order two-tone intermodulation distortion Each tone at -12 dBFS | f _{DAC} = 800 MSPS, f _{OUT} = 30 ± 0.5 MHz | | 93 | | dBc |
| | | f _{DAC} = 800 MSPS, f _{OUT} = 50 ± 0.5 MHz | | 90 | | |
| | | f _{DAC} = 800 MSPS, f _{OUT} = 100 ± 0.5 MHz | | 86 | | |
| NSD | Noise spectral density tone at 0dBFS | f _{DAC} = 800 MSPS, f _{OUT} = 10.1 MHz | | 162 | | dBc/Hz |
| | | f _{DAC} = 800 MSPS, f _{OUT} = 80.1 MHz | | 160 | | |
| WCDMA ⁽³⁾ | Adjacent channel leakage ratio, single carrier | f _{DAC} = 737.28 MSPS, f _{OUT} = 30.72MHz | | 85 | | dBc |
| | | f _{DAC} = 737.28 MSPS, f _{OUT} = 153.6MHz | | 81 | | |
| | Alternate channel leakage ratio, single carrier | f _{DAC} = 737.28 MSPS, f _{OUT} = 30.72MHz | | 91 | | dBc |
| | | f _{DAC} = 737.28 MSPS, f _{OUT} = 153.6MHz | | 85 | | |
| | Channel isolation | f _{DAC} = 800 MSPS, f _{OUT} = 10MHz | | 84 | | dBc |

(1) Measured single-ended into 50Ω load.

(2) 4:1 transformer output termination, 50Ω doubly terminated load

(3) Single carrier, W-CDMA with 3.84 MHz BW, 5-MHz spacing, centered at f_{OUT}, PAR = 12dB. TESTMODEL 1, 10 ms

ELECTRICAL CHARACTERISTICS – DIGITAL SPECIFICATIONS

over recommended operating free-air temperature range, nominal supplies, IOUTFS = 20 mA (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--|--|---|-------------------------|------|------------------------------------|------|
| LVDS INTERFACE: D[7:0]P/N, DATACLKP/N, FRAMEP/N ⁽¹⁾ | | | | | | |
| f _{DATA} | Input data rate | Byte-wide DDR format DATACLK frequency = 625 MHz | | | 312.5 | MSPS |
| f _{BUS} | Byte-wide LVDS data transfer rate | | | | 1250 | MSPS |
| V _{A,B+} | Logic high differential input voltage threshold | | 150 | 400 | | mV |
| V _{A,B-} | Logic low differential input voltage threshold | | -150 | -400 | | mV |
| V _{COM} | Input common mode | | 0.9 | 1.2 | 1.5 | V |
| Z _T | Internal termination | | 85 | 110 | 135 | Ω |
| C _L | LVDS Input capacitance | | | 2 | | pF |
| TIMING LVDS INPUTS: DATACLKP/N DOUBLE EDGE LATCHING – See Figure 40 | | | | | | |
| t _{s(DATA)} | Setup time, D[7:0]P/N and FRAMEP/N, valid to either edge of DATACLKP/N | FRAMEP/N latched on rising edge of DATACLKP/N only | -25 | | | ps |
| t _{h(DATA)} | Hold time, D[7:0]P/N and FRAMEP/N, valid after either edge of DATACLKP/N | FRAMEP/N latched on rising edge of DATACLKP/N only | 375 | | | ps |
| t _{f(FRAME)} | FRAMEP/N pulse width | f _{DATACLK} is DATACLK frequency in MHz | 1/2f _{DATACLK} | | | ns |
| t _{align} | Maximum offset between DATACLKP/N and DACCLKP/N rising edges | FIFO bypass mode only f _{DACCLK} is DACCLK frequency in MHz | | | 1/2f _{DACCLK} -0.55 | ns |
| CLOCK INPUT (DACCLKP/N) | | | | | | |
| | Duty cycle | | 40% | | 60% | |
| | Differential voltage ⁽²⁾ | | 0.4 | 1.0 | | V |
| | DACCLKP/N Input Frequency | | | | 800 | MHz |
| OUTPUT STROBE (OSTRP/N) | | | | | | |
| f _{OSTR} | Frequency | f _{OSTR} = f _{DACCLK} / (n × 8 × Interp) where n is any positive integer f _{DACCLK} is DACCLK frequency in MHz | | | f _{DACCLK} / (8 × interp) | |
| | Duty cycle | | 40% | | 60% | |
| | Differential voltage | | 0.4 | 1.0 | | V |
| TIMING OSTRP/N INPUT: DACCLKP/N RISING EDGE LATCHING | | | | | | |
| t _{s(OSTR)} | Setup time, OSTRP/N valid to rising edge of DACCLKP/N | | | 200 | | ps |
| t _{h(OSTR)} | Hold time, OSTRP/N valid after rising edge of DACCLKP/N | | | 200 | | ps |
| CMOS INTERFACE: ALARM_SDO, SDIO, SCLK, SDENB, TXENABLE | | | | | | |
| V _{IH} | High-level input voltage | | 1.25 | | | V |
| V _{IL} | Low-level input voltage | | | | 0.54 | V |
| I _{IH} | High-level input current | | -40 | | 40 | μA |
| I _{IL} | Low-level input current | | -40 | | 40 | μA |
| CI | CMOS input capacitance | | | 2 | | pF |
| V _{OH} | ALARM_SDO, SDIO | I _{load} = -100 μA | DIGVDD18 -0.2 | | | V |
| | | I _{load} = -2mA | 0.8 x DIGVDD18 | | | V |
| V _{OL} | ALARM_SDO, SDIO | I _{load} = 100 μA | | | 0.2 | V |
| | | I _{load} = 2 mA | | | 0.5 | V |
| SERIAL PORT TIMING – See Figure 32 and Figure 33 | | | | | | |
| t _{s(SDENB)} | Setup time, SDENB to rising edge of SCLK | | 20 | | | ns |
| t _{s(SDIO)} | Setup time, SDIO valid to rising edge of SCLK | | 10 | | | ns |
| t _{h(SDIO)} | Hold time, SDIO valid to rising edge of SCLK | | 5 | | | ns |
| t _{f(SCLK)} | Period of SCLK | Register CONFIG5 read (temperature sensor read) | 1 | | | μs |
| | | All other registers | 100 | | | ns |

(1) See LVDS INPUTS section for terminology.

(2) Driving the clock input with a differential voltage lower than 1V will result in degraded performance.

ELECTRICAL CHARACTERISTICS – DIGITAL SPECIFICATIONS (continued)

over recommended operating free-air temperature range, nominal supplies, IOUTFS = 20 mA (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------|--|---|-----|-----|-----|---------|
| $t_{(SCLKH)}$ | High time of SCLK | Register CONFIG5 read (temperature sensor read) | 0.4 | | | μ s |
| | | All other registers | 40 | | | ns |
| $t_{(SCLKL)}$ | Low time of SCLK | Register CONFIG5 read (temperature sensor read) | 0.4 | | | μ s |
| | | All other registers | 40 | | | ns |
| $t_{d(Data)}$ | Data output delay after falling edge of SCLK | | | 10 | | ns |

TYPICAL CHARACTERISTICS

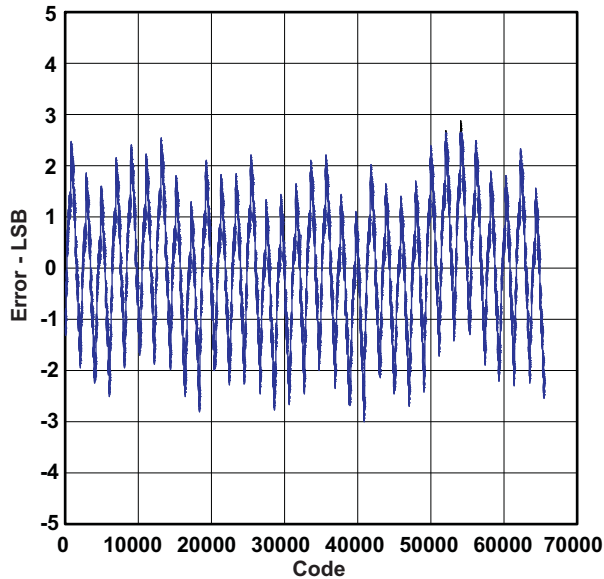


Figure 1. INTEGRAL NON-LINEARITY

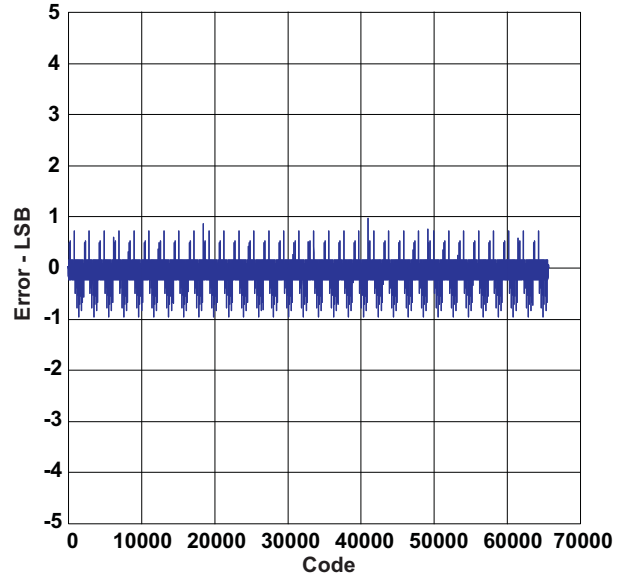


Figure 2. DIFFERENTIAL NON-LINEARITY

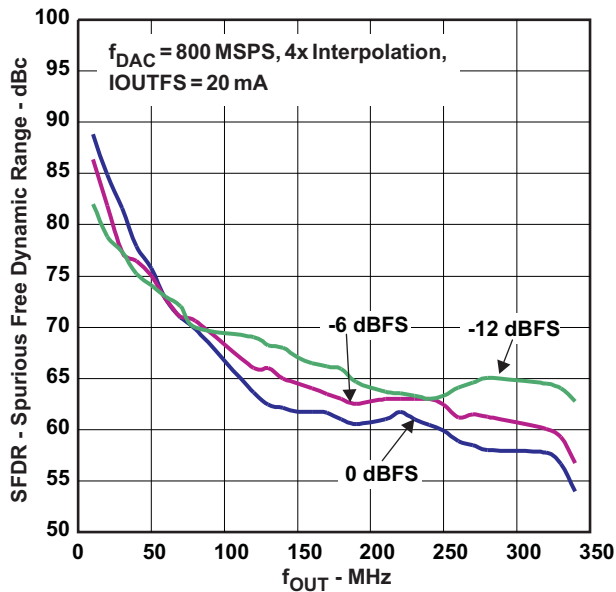


Figure 3. SPURIOUS FREE DYNAMIC RANGE vs INPUT SCALE

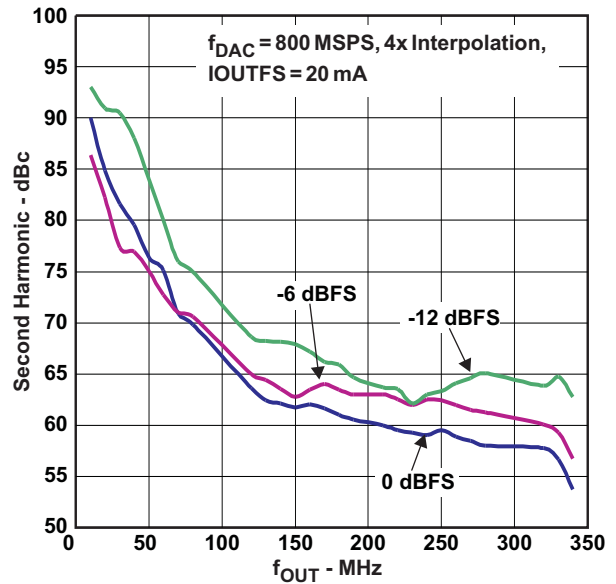


Figure 4. SECOND HARMONIC vs INPUT SCALE

TYPICAL CHARACTERISTICS (continued)

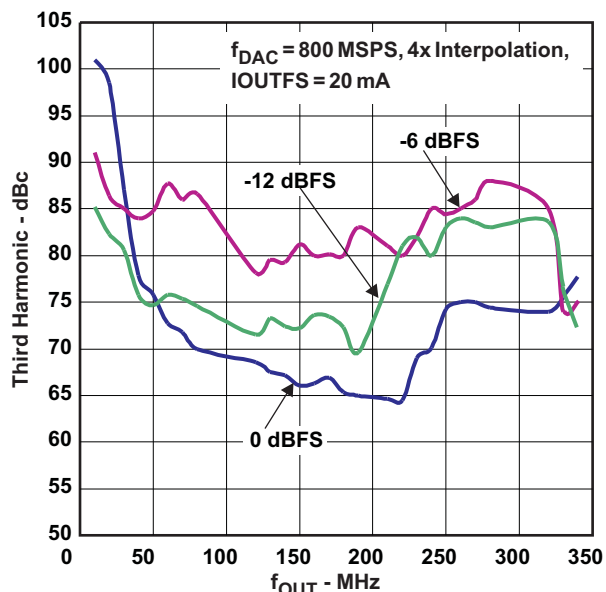


Figure 5. THIRD HARMONIC vs INPUT SCALE

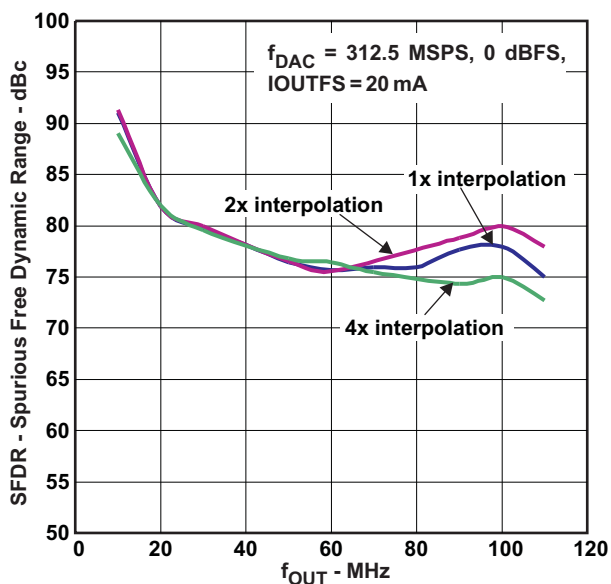


Figure 6. SPURIOUS FREE DYNAMIC RANGE vs INTERPOLATION

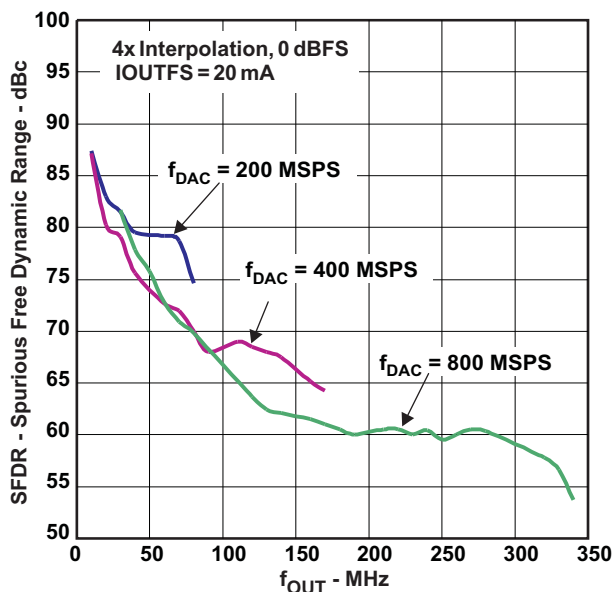


Figure 7. SPURIOUS FREE DYNAMIC RANGE vs f_{DAC}

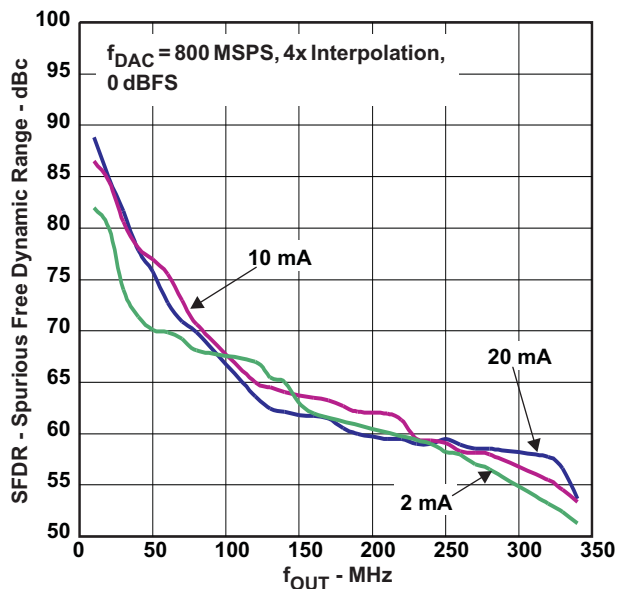


Figure 8. SPURIOUS FREE DYNAMIC RANGE vs IOUTFS

TYPICAL CHARACTERISTICS (continued)

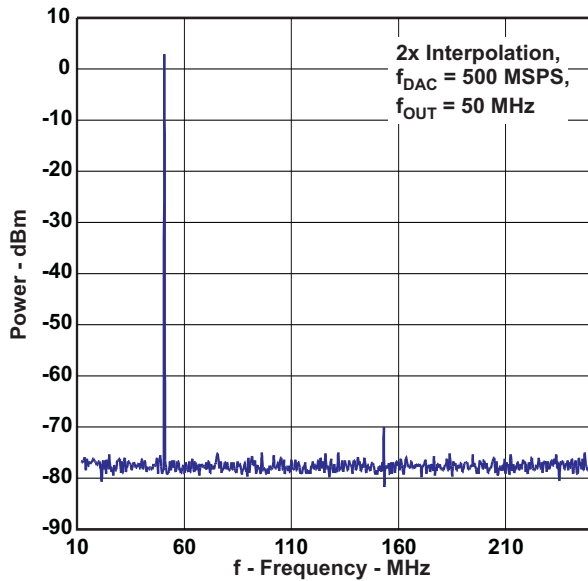


Figure 9. SINGLE TONE SPECTRAL PLOT

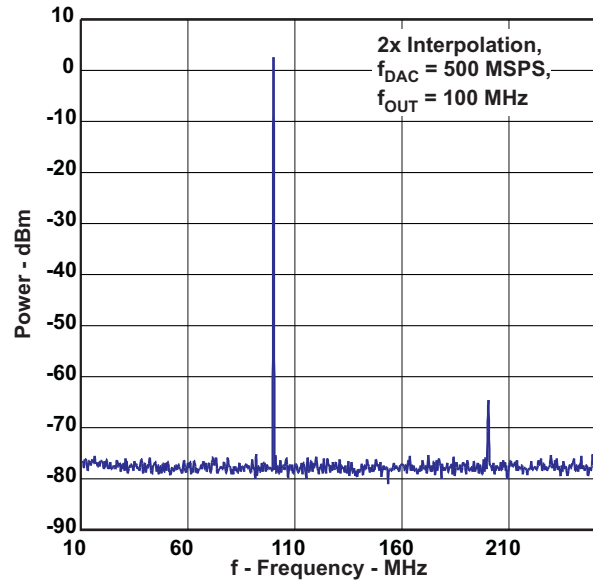


Figure 10. SINGLE TONE SPECTRAL PLOT

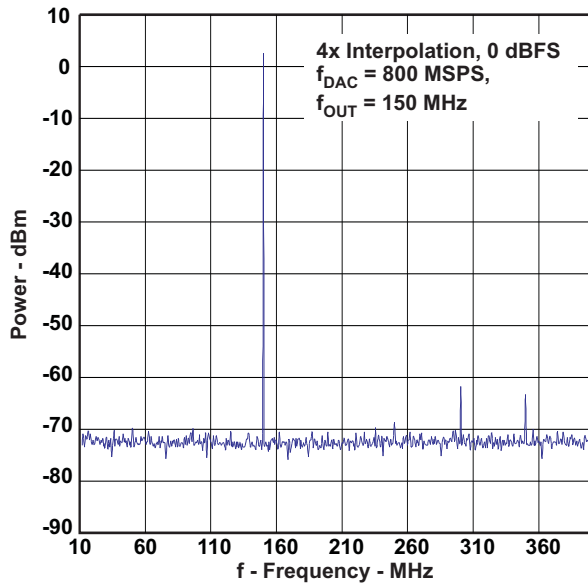


Figure 11. SINGLE TONE SPECTRAL PLOT

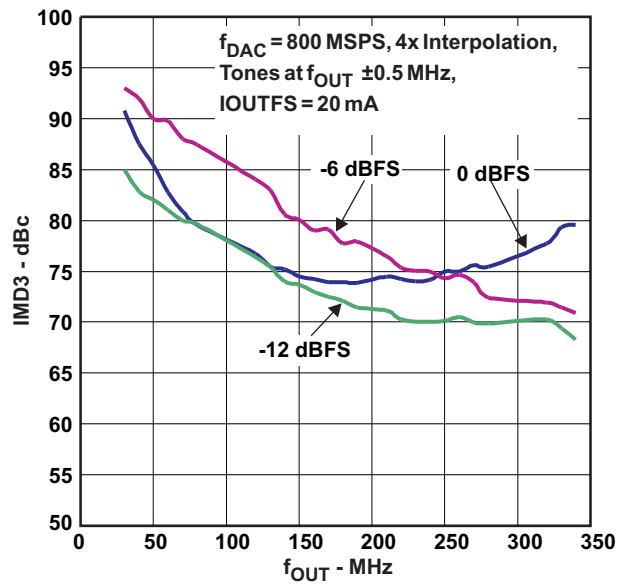


Figure 12. IMD3 vs INPUT SCALE

TYPICAL CHARACTERISTICS (continued)

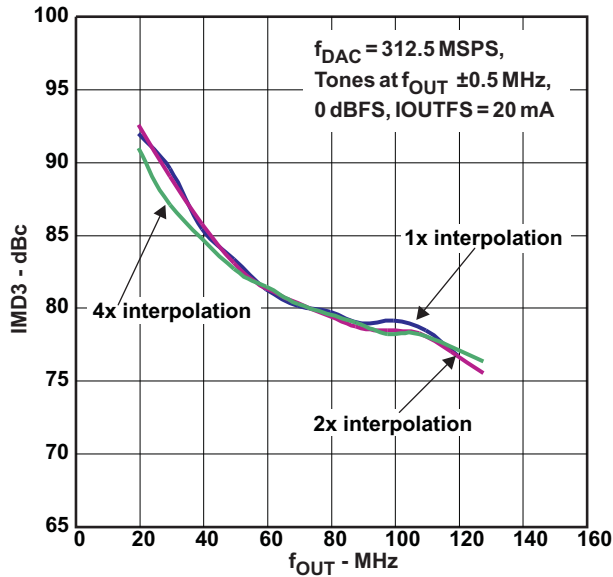


Figure 13. IMD3 vs INTERPOLATION

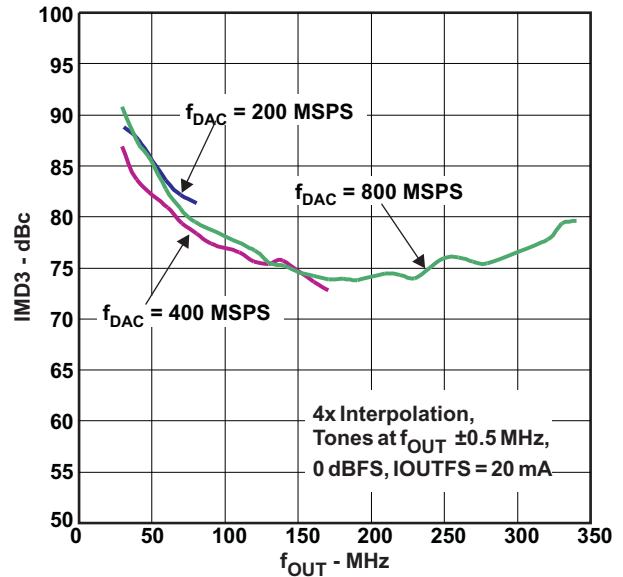


Figure 14. IMD3 vs f_{DAC}

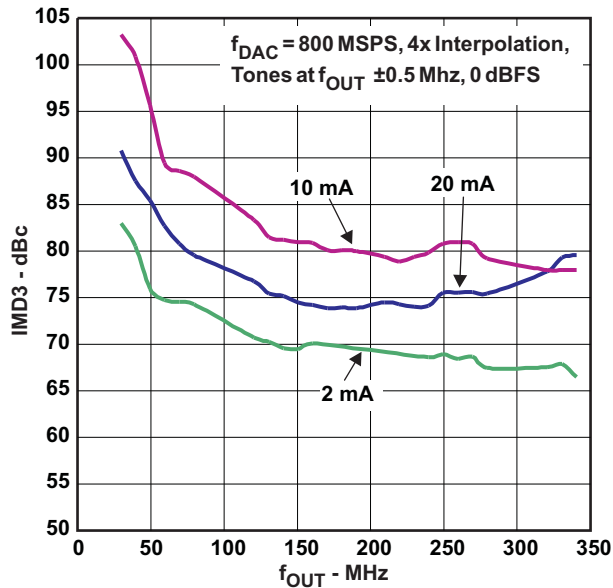


Figure 15. IMD3 vs I_{OUTFS}

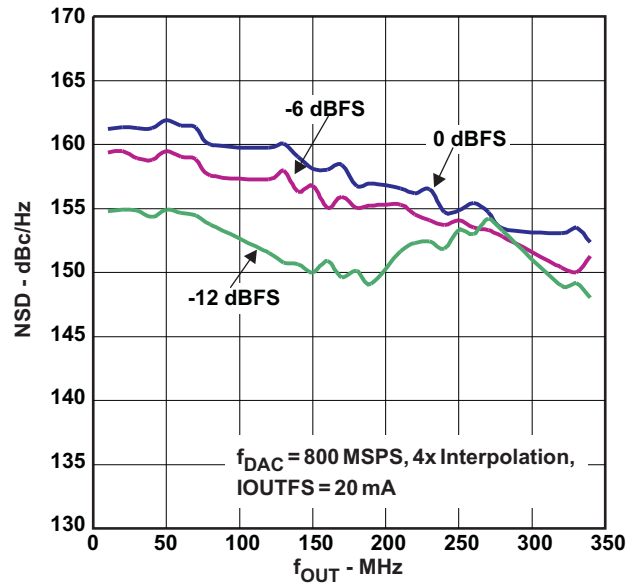


Figure 16. NSD vs INPUT SCALE

TYPICAL CHARACTERISTICS (continued)

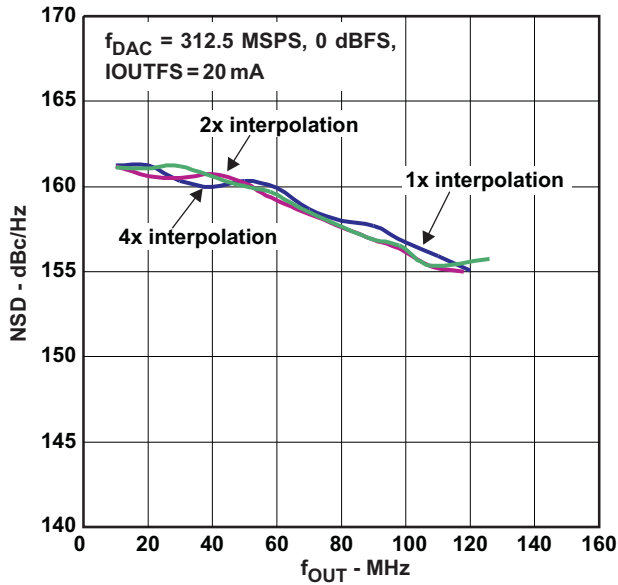


Figure 17. NSD vs INTERPOLATION

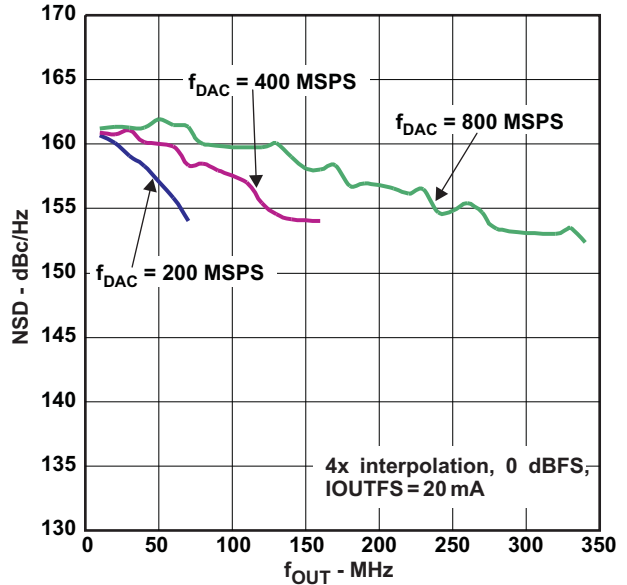


Figure 18. NSD vs f_{DAC}

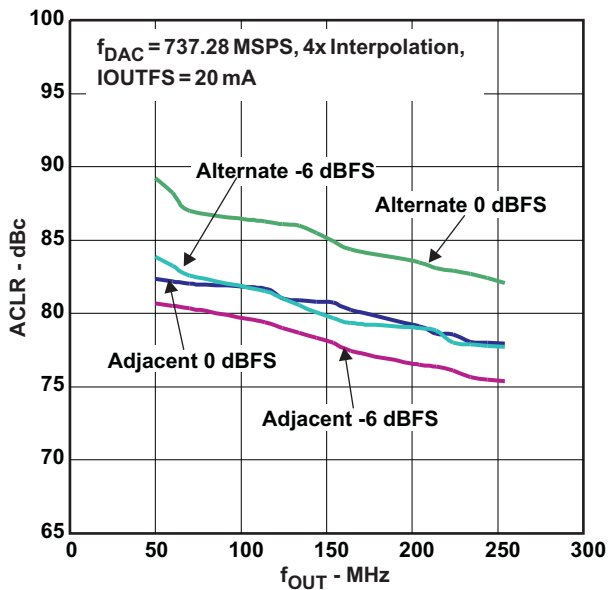


Figure 19. SINGLE CARRIER WCDMA ACLR vs INPUT SCALE

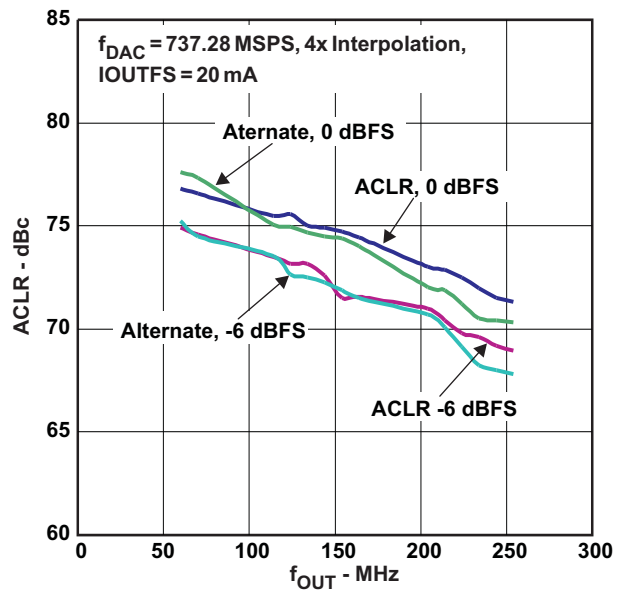


Figure 20. FOUR CARRIER WCDMA ACLR vs INPUT SCALE

TYPICAL CHARACTERISTICS (continued)

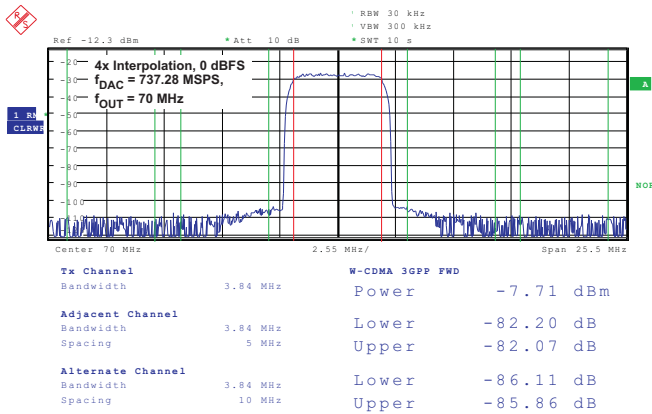


Figure 21. SINGLE CARRIER W-CDMA TEST MODEL 1

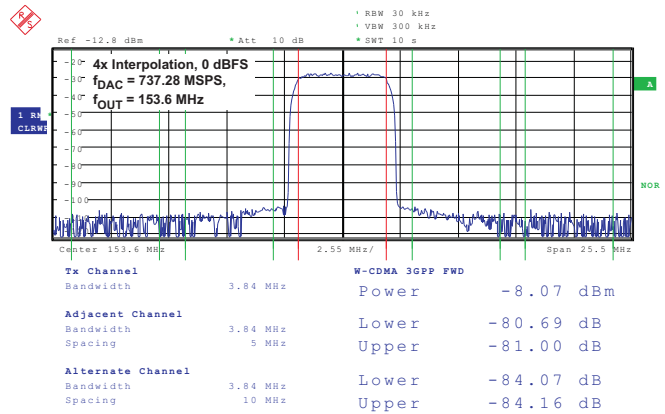


Figure 22. SINGLE CARRIER W-CDMA TEST MODEL 1

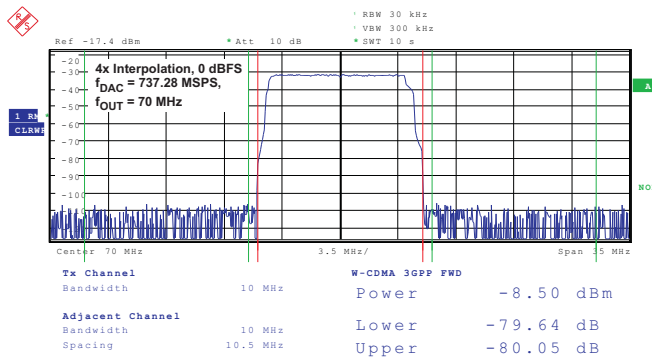


Figure 23. 10MHZ SINGLE CARRIER LTE

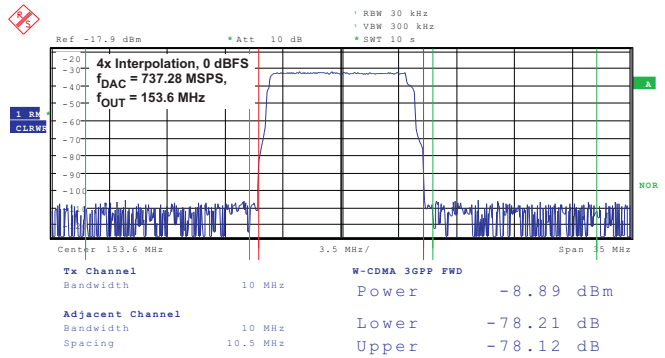


Figure 24. 10MHZ SINGLE CARRIER LTE

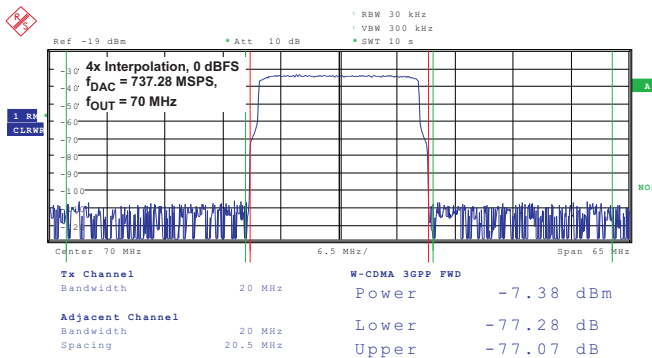


Figure 25. 20MHZ SINGLE CARRIER LTE

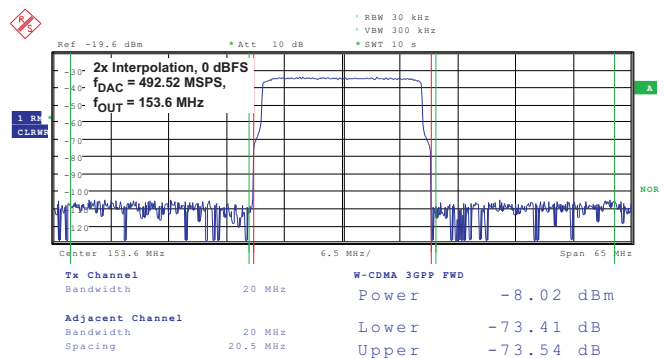


Figure 26. 20MHZ SINGLE CARRIER LTE

TYPICAL CHARACTERISTICS (continued)

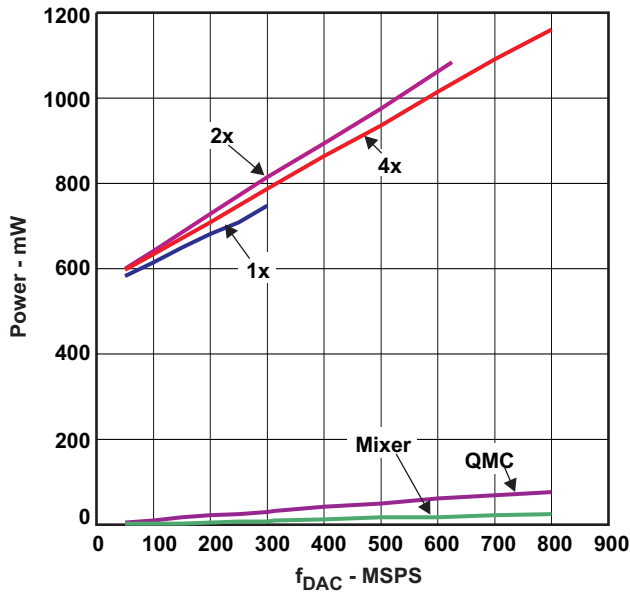


Figure 27. POWER vs f_{DAC}

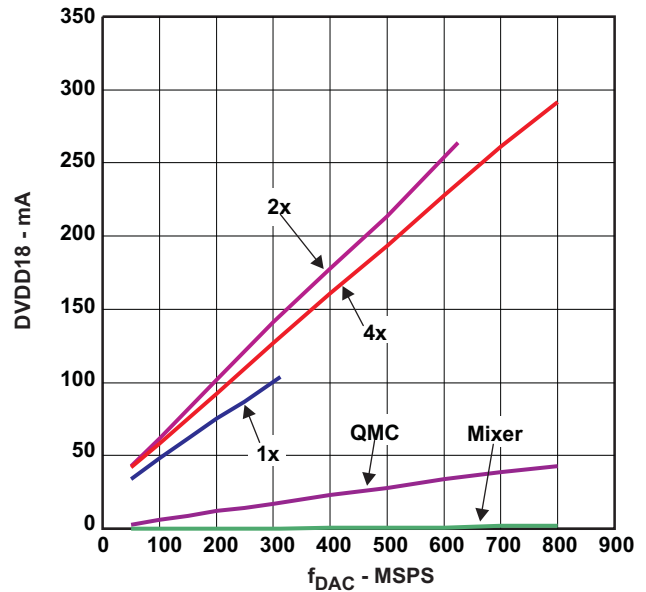


Figure 28. DVDD18 vs f_{DAC}

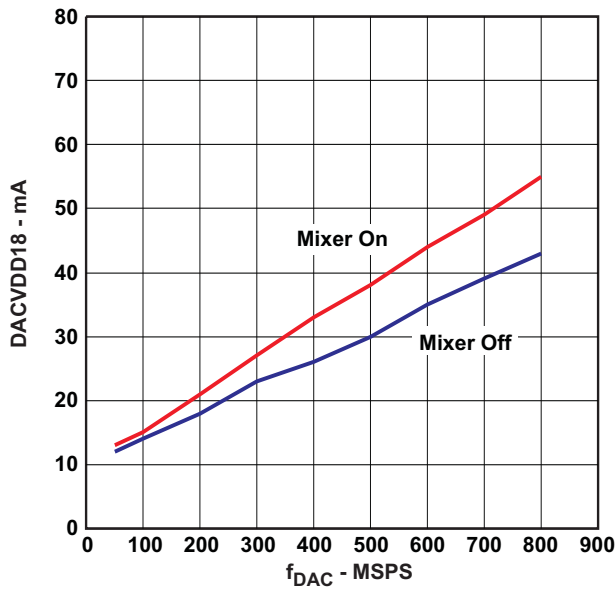


Figure 29. DACVDD18 vs f_{DAC}

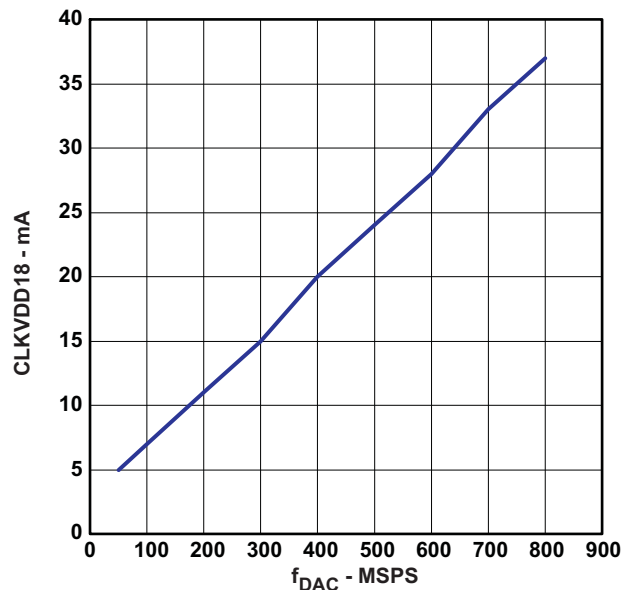


Figure 30. CLKVDD18 vs f_{DAC}

TYPICAL CHARACTERISTICS (continued)

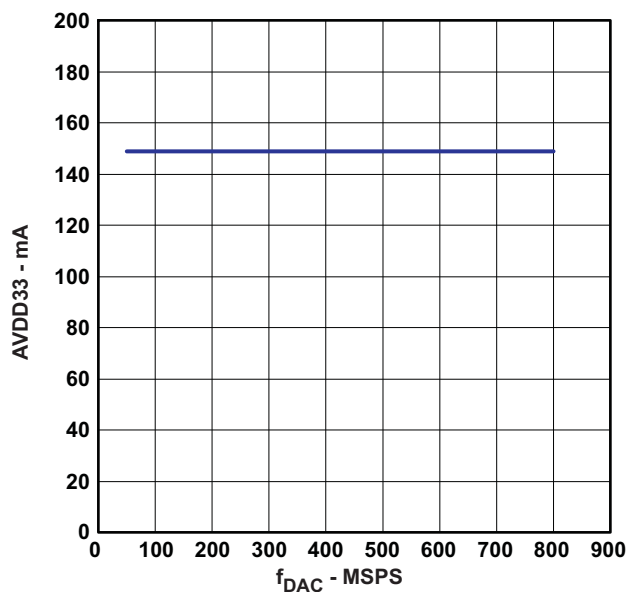


Figure 31. AVDD33 vs f_{DAC}

FUNCTIONAL DESCRIPTION

DEFINITION OF SPECIFICATIONS

Adjacent Carrier Leakage Ratio (ACLR): Defined for a 3.84Mcps 3GPP W-CDMA input signal measured in a 3.84MHz bandwidth at a 5MHz offset from the carrier with a 12dB peak-to-average ratio.

Analog and Digital Power Supply Rejection Ratio (APSSR, DPSSR): Defined as the percentage error in the ratio of the delta IOUT and delta supply voltage normalized with respect to the ideal IOUT current.

Differential Nonlinearity (DNL): Defined as the variation in analog output associated with an ideal 1 LSB change in the digital input code.

Gain Drift: Defined as the maximum change in gain, in terms of ppm of full-scale range (FSR) per °C, from the value at ambient (25°C) to values over the full operating temperature range.

Gain Error: Defined as the percentage error (in FSR%) for the ratio between the measured full-scale output current and the ideal full-scale output current.

Integral Nonlinearity (INL): Defined as the maximum deviation of the actual analog output from the ideal output, determined by a straight line drawn from zero scale to full scale.

Intermodulation Distortion (IMD3, IMD): The two-tone IMD3 or four-tone IMD is defined as the ratio (in dBc) of the worst 3rd-order (or higher) intermodulation distortion product to either fundamental output tone.

Offset Drift: Defined as the maximum change in DC offset, in terms of ppm of full-scale range (FSR) per °C, from the value at ambient (25°C) to values over the full operating temperature range.

Offset Error: Defined as the percentage error (in FSR%) for the ratio between the measured mid-scale output current and the ideal mid-scale output current.

Output Compliance Range: Defined as the minimum and maximum allowable voltage at the output of the current-output DAC. Exceeding this limit may result reduced reliability of the device or adversely affecting distortion performance.

Reference Voltage Drift: Defined as the maximum change of the reference voltage in ppm per degree Celsius from value at ambient (25°C) to values over the full operating temperature range.

Spurious Free Dynamic Range (SFDR): Defined as the difference (in dBc) between the peak amplitude of the output signal and the peak spurious signal.

Signal to Noise Ratio (SNR): Defined as the ratio of the RMS value of the fundamental output signal to the RMS sum of all other spectral components below the Nyquist frequency, including noise, but excluding the first six harmonics and dc.

REGISTER DESCRIPTIONS
Table 1. Register Map

| Name | Address | Default | (MSB) Bit 7 | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | (LSB) Bit 0 | |
|----------|---------|---------|----------------------|-------------------|----------------------|------------------|-------------------|-----------------|-------------------|------------------|--|
| CONFIG0 | 0x00 | 0x70 | reserved | fifo_ena | fifo_reset_ena | multi_sync_ena | alarm_out_ena | alarm_pol | mixer_func(1:0) | | |
| CONFIG1 | 0x01 | 0x11 | qmc_offset_ena | qmc_correct_ena | fir0_ena | fir1_ena | unused | iotest_ena | unused | twos | |
| CONFIG2 | 0x02 | 0x00 | unused | unused | sif_sync | sif_sync_ena | unused | unused | output_delay(1:0) | | |
| CONFIG3 | 0x03 | 0x10 | 64cnt_ena | unused | unused | fifo_offset(2:0) | | alarm_2away_ena | alarm_1away_ena | | |
| CONFIG4 | 0x04 | 0xFF | coarse_daca(3:0) | | | | coarse_dacb(3:0) | | | | |
| CONFIG5 | 0x05 | N/A | tempdata(7:0) | | | | | | | | |
| CONFIG6 | 0x06 | 0x00 | unused | alarm_mask(6:0) | | | | | | | |
| CONFIG7 | 0x07 | 0x00 | unused | alarm_from_zerock | alarm_fifo_collision | reserved | alarm_from_iotest | unused | alarm_fifo_2away | alarm_fifo_1away | |
| CONFIG8 | 0x08 | 0x00 | iotest_results(7:0) | | | | | | | | |
| CONFIG9 | 0x09 | 0x7A | iotest_pattern0(7:0) | | | | | | | | |
| CONFIG10 | 0x0A | 0xB6 | iotest_pattern1(7:0) | | | | | | | | |
| CONFIG11 | 0x0B | 0xEA | iotest_pattern2(7:0) | | | | | | | | |
| CONFIG12 | 0x0C | 0x45 | iotest_pattern3(7:0) | | | | | | | | |
| CONFIG13 | 0x0D | 0x1A | iotest_pattern4(7:0) | | | | | | | | |
| CONFIG14 | 0x0E | 0x16 | iotest_pattern5(7:0) | | | | | | | | |
| CONFIG15 | 0x0F | 0xAA | iotest_pattern6(7:0) | | | | | | | | |
| CONFIG16 | 0x10 | 0xC6 | iotest_pattern7(7:0) | | | | | | | | |
| CONFIG17 | 0x11 | 0x24 | reserved | reserved | reserved | clk_alarm_mask | tx_off_mask | reserved | clk_alarm_ena | tx_off_ena | |
| CONFIG18 | 0x12 | 0x02 | reserved | | | reserved | daca_complement | dacb_complement | clkdiv_sync_ena | unused | |
| CONFIG19 | 0x13 | 0x00 | bequalsa | aequalsb | reserved | unused | unused | unused | multi_sync_sel | rev | |
| CONFIG20 | 0x14 | 0x00 | qmc_offseta(7:0) | | | | | | | | |
| CONFIG21 | 0x15 | 0x00 | qmc_offsetb(7:0) | | | | | | | | |
| CONFIG22 | 0x16 | 0x00 | qmc_offseta(12:8) | | | | | unused | unused | unused | |
| CONFIG23 | 0x17 | 0x00 | qmc_offsetb(12:8) | | | | | sif4_ena | clkpath_sleep_a | clkpath_sleep_b | |
| CONFIG24 | 0x18 | 0x83 | tsense_ena | clkrecv_sleep | unused | reserved | sleepb | sleepa | reserved | reserved | |
| CONFIG25 | 0x19 | 0x00 | reserved | | | | | extref_ena | reserved | reserved | |
| CONFIG26 | 0x1A | 0x00 | reserved | | reserved | | unused | reserved | | | |
| CONFIG27 | 0x1B | 0x00 | qmc_gaina(7:0) | | | | | | | | |
| CONFIG28 | 0x1C | 0x00 | qmc_gainb(7:0) | | | | | | | | |
| CONFIG29 | 0x1D | 0x00 | qmc_phase(7:0) | | | | | | | | |
| CONFIG30 | 0x1E | 0x24 | qmc_phase(9:8) | | | qmc_gaina(10:8) | | | qmc_gainb(10:8) | | |
| CONFIG31 | 0x1F | 0x52 | clk_alarm | tx_off | version(5:0) | | | | | | |

Register name: CONFIG0 – Address: 0x00, Default = 0x70

| Register Name | Address | Bit | Name | Function | Default Value | | | | | | | | | |
|------------------|-----------------|-----|--|--|-----------------|--------|----|------------------|----|------|----|-------|----|--|
| CONFIG0 | 0x00 | 7 | qmc_offset_ena | When asserted the DAC offset correction is enabled. | 0 | | | | | | | | | |
| | | 6 | fifo_ena | When asserted the FIFO is enabled. When the FIFO is bypassed DACCLKP/N and DATACLKP/N must be aligned to within t_align. | 1 | | | | | | | | | |
| | | 5 | fifo_reset_ena | Allows the FRAME input to act as a FIFO write reset when asserted. | 1 | | | | | | | | | |
| | | 4 | multi_sync_ena | Allows the FRAME or OSTR signals to be used as a sync signal when asserted. This selection is determined by multi_sync_sel in register CONFIG19. | 1 | | | | | | | | | |
| | | 3 | alarm_out_ena | When asserted the ALARM_SDO pin becomes an output. The functionality of this pin is controlled by the CONFIG6 alarm_mask setting. | 0 | | | | | | | | | |
| | | 2 | alarm_pol | This bit changes the polarity of the ALARM signal. (0=negative logic, 1=positive logic) | 0 | | | | | | | | | |
| | | 1:0 | mixer_func(1:0) | Controls the function of the mixer block. | 00 | | | | | | | | | |
| | | | <table border="1"> <thead> <tr> <th>Mode</th> <th>mixer_func(1:0)</th> </tr> </thead> <tbody> <tr> <td>Normal</td> <td>00</td> </tr> <tr> <td>High Pass (Fs/2)</td> <td>01</td> </tr> <tr> <td>Fs/4</td> <td>10</td> </tr> <tr> <td>-Fs/4</td> <td>11</td> </tr> </tbody> </table> | Mode | mixer_func(1:0) | Normal | 00 | High Pass (Fs/2) | 01 | Fs/4 | 10 | -Fs/4 | 11 | |
| Mode | mixer_func(1:0) | | | | | | | | | | | | | |
| Normal | 00 | | | | | | | | | | | | | |
| High Pass (Fs/2) | 01 | | | | | | | | | | | | | |
| Fs/4 | 10 | | | | | | | | | | | | | |
| -Fs/4 | 11 | | | | | | | | | | | | | |

Register name: CONFIG1 – Address: 0x01, Default = 0x11

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-----------------|--|---------------|
| CONFIG1 | 0x01 | 7 | qmc_offset_ena | When asserted the QMC offset correction circuitry is enabled. | 0 |
| | | 6 | qmc_correct_ena | When asserted the QMC phase and gain correction circuitry is enabled. | 0 |
| | | 5 | fir0_ena | When asserted FIR0 is activated enabling 2x interpolation. | 0 |
| | | 4 | fir1_ena | When asserted FIR1 is activated enabling 4x interpolation. fir0_ena must be set to '1' for 4x interpolation. | 1 |
| | | 3 | Unused | Reserved for factory use. | 0 |
| | | 2 | iotest_ena | When asserted enables the data pattern checker operation. | 0 |
| | | 1 | Unused | Reserved for factory use. | 0 |
| | | 0 | twos | When asserted the inputs are expected to be in 2's complement format. When de-asserted the input format is expected to be offset-binary. | 1 |

Register name: CONFIG2 – Address: 0x02, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-------------------|--|---------------|
| CONFIG2 | 0x02 | 7 | Unused | Reserved for factory use. | 0 |
| | | 6 | Unused | Reserved for factory use. | 0 |
| | | 5 | sif_sync | Serial interface created sync signal. Set to '1' to cause a sync and then clear to '0' to remove it. | 0 |
| | | 4 | sif_sync_ena | When asserted this bit allows the SIF sync to be used. Normal FIFO_ISTR signals are ignored. | 0 |
| | | 3 | Unused | Reserved for factory use. | 0 |
| | | 2 | Unused | Reserved for factory use. | 0 |
| | | 1:0 | output_delay(1:0) | Delays the output to the DACs from 0 to 3 DAC clock cycles. | 00 |

Register name: CONFIG3 – Address: 0x03, Default = 0x10

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|------------------|--|---------------|
| CONFIG1 | 0x03 | 7 | 64cnt_ena | This enables resetting the alarms after 64 good samples with the goal of removing unnecessary errors. For instance, when checking setup/hold through the pattern checker test, there may initially be errors. Setting this bit removes the need for a SIF write to clear the alarm register. | 0 |
| | | 6 | Unused | Reserved for factory use. | 0 |
| | | 5 | Unused | Reserved for factory use. | 0 |
| | | 4:2 | fifo_offset(2:0) | When the FIFO is reset, this is the value loaded into the FIFO read pointer. With this value the initial difference between write and read pointers can be controlled. This may be helpful in controlling the delay through the device. | 100 |
| | | 1 | alarm_2away_ena | When asserted alarms from the FIFO that represent the write and read pointers being 2 away are enabled. | 0 |
| | | 0 | alarm_1away_ena | When asserted alarms from the FIFO that represent the write and read pointers being 1 away are enabled. | 0 |

Register name: CONFIG4 – Address: 0x04, Default = 0xFF

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|------------------|--|---------------|
| CONFIG4 | 0x04 | 7:4 | coarse_daca(3:0) | Scales the DACA output current in 16 equal steps. $\frac{V_{EXTIO}}{R_{bias}} \times (\text{coarse_daca}/b + 1)$ | 1111 |
| | | 3:0 | coarse_dacb(3:0) | Scales the DACB output current in 16 equal steps. | 1111 |

Register name: CONFIG5 – Address: 0x05, READ ONLY

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|---------------|--|---------------|
| CONFIG5 | 0x05 | 7:0 | tempdata(7:0) | This is the output from the chip temperature sensor. The value of this register in two's complement format represents the temperature in degrees Celsius. This register must be read with a minimum SCLK period of 1µs. (Read Only) | N/A |

Register name: CONFIG6 – Address: 0x06, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value | | |
|---------------|---------|-----|-----------------|--|---------------|-------------------|----------------------|
| CONFIG6 | 0x06 | 7 | Unused | Reserved for factory use. | 0 | | |
| | | 6:0 | alarm_mask(6:0) | These bits control the masking of the alarm outputs. This means that the ALARM_SDO pin will not be asserted if the appropriate bit is set. The alarm will still show up in the CONFIG7 bits. (0=not masked, 1=masked). | 0000000 | | |
| | | | | | | alarm_mask | Masked Alarm |
| | | | | | | 6 | alarm_from_zerochk |
| | | | | | | 5 | alarm_fifo_collision |
| | | | | | | 4 | reserved |
| | | | | | | 3 | alarm_from_iotest |
| | | | | | | 2 | not used (expansion) |
| | | | | | | 1 | alarm_fifo_2away |
| | | | | | | 0 | alarm_fifo_1away |

Register name: CONFIG7 – Address: 0x07, Default = 0x00 (WRITE TO CLEAR)

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG7 | 0x07 | 7 | Unused | Reserved for factory use. | 0 |
| | | 6 | alarm_from_zerochk | When this bit is asserted the FIFO write pointer has an all zeros pattern in it. Since this pointer is a shift register, all zeros will cause the input point to be stuck until the next sync. This alarm allows checking for this condition. | 0 |
| | | 5 | alarm_fifo_collision | Alarm occurs when the FIFO pointers over/under run each other. | 0 |
| | | 4 | Reserved | When asserted the chip does 2X interpolation of the data. | 0 |
| | | 3 | alarm_from_iotest | This is asserted when the input data pattern does not match the pattern in the iotest_pattern registers. | 0 |
| | | 2 | Unused | When asserted enables the data pattern checker operation. | 0 |
| | | 1 | alarm_fifo_2away | Alarm occurs with the read and write pointers of the FIFO are within 2 addresses of each other. | 0 |
| | | 0 | alarm_fifo_1away | Alarm occurs with the read and write pointers of the FIFO are within 1 address of each other. | 0 |

Register name: CONFIG8 – Address: 0x08, Default = 0x00 (WRITE TO CLEAR)

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|---------------------|---|---------------|
| CONFIG8 | 0x08 | 7:0 | iotest_results(7:0) | The values of these bits tell which bit in the word failed during the pattern checker test. | 0x00 |

Register name: CONFIG9 – Address: 0x09, Default = 0x7A

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG9 | 0x09 | 7:0 | iotest_pattern0(7:0) | This is dataword0 in the IO test pattern. It is used with the seven other words to test the input data. | 0x7A |

Register name: CONFIG10 – Address: 0x0A, Default = 0xB6

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG10 | 0x0A | 7:0 | iotest_pattern1(7:0) | This is dataword1 in the IO test pattern. It is used with the seven other words to test the input data. | 0xB6 |

Register name: CONFIG11 – Address: 0x0B, Default = 0xEA

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG11 | 0x0B | 7:0 | iotest_pattern2(7:0) | This is dataword2 in the IO test pattern. It is used with the seven other words to test the input data. | 0xEA |

Register name: CONFIG12 – Address: 0x0C, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG12 | 0x0C | 7:0 | iotest_pattern3(7:0) | This is dataword3 in the IO test pattern. It is used with the seven other words to test the input data. | 0x45 |

Register name: CONFIG13 – Address: 0x0D, Default = 0x1A

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG13 | 0x0D | 7:0 | iotest_pattern4(7:0) | This is dataword4 in the IO test pattern. It is used with the seven other words to test the input data. | 0x1A |

Register name: CONFIG14 – Address: 0x0E, Default = 0x16

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG14 | 0x0E | 7:0 | iotest_pattern5(7:0) | This is dataword5 in the IO test pattern. It is used with the seven other words to test the input data. | 0x16 |

Register name: CONFIG15 – Address: 0x0F, Default = 0xAA

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG15 | 0x0F | 7:0 | iotest_pattern6(7:0) | This is dataword6 in the IO test pattern. It is used with the seven other words to test the input data. | 0xAA |

Register name: CONFIG16 – Address: 0x10, Default = 0xC6

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------------|---|---------------|
| CONFIG16 | 0x10 | 7:0 | iotest_pattern7(7:0) | This is dataword7 in the IO test pattern. It is used with the seven other words to test the input data. | 0xC6 |

Register name: CONFIG17 – Address: 0x11, Default = 0x24

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------|---|---------------|
| CONFIG17 | 0x11 | 7 | Reserved | Reserved for factory use. | 0 |
| | | 6 | Reserved | Reserved for factory use. | 0 |
| | | 5 | Reserved | Reserved for factory use. | 1 |
| | | 4 | clk_alarm_mask | This bit controls the masking of the clock monitor alarm. This means that the ALARM_SDO pin will not be asserted. The alarm will still show up in the clk_alarm bit. (0=not masked, 1= masked). | 0 |
| | | 3 | tx_off_mask | This bit control the masking of the transmit enable alarm. This means that the ALARM_SDO pin will not be asserted. The alarm will still show up in the tx_off bit. (0=not masked, 1= masked). | 0 |
| | | 2 | Reserved | Reserved for factory use. | 1 |
| | | 1 | clk_alarm_ena | When asserted the DATACLK monitor alarm is enabled. | 0 |
| | | 0 | tx_off_ena | When asserted a clk_alarm event will automatically disable the DAC outputs by setting them to midscale. | 0 |

Register name: CONFIG18 – Address: 0x12, Default = 0x02

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-----------------|---|---------------|
| CONFIG18 | 0x12 | 7:5 | Reserved | Reserved for factory use. | 000 |
| | | 4 | Reserved | Reserved for factory use. | 0 |
| | | 3 | daca_complement | When asserted the output to the DACA is complemented. This allows to effectively change the + and – designations of the LVDS data lines. | 0 |
| | | 2 | dacb_complement | When asserted the output to the DACB is complemented. This allows to effectively change the + and – designations of the LVDS data lines. | 0 |
| | | 1 | clkdiv_sync_ena | Enables the syncing of the clock divider using the OSTR signal or the FRAME signal passed through the FIFO. This selection is determined by multi_sync_sel in register CONFIG19. Syncing of the clock divider should be done only during device initialization. | 1 |
| | | 0 | Unused | Reserved for factory use. | 0 |

Register name: CONFIG19 – Address: 0x13, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value | | | | | |
|----------------|----------------------------|-----|----------------|---|---------------|----------------|-------------|---|------|---|
| CONFIG19 | 0x13 | 7 | bequalsa | When asserted the DACA data is driven onto DACB. | 0 | | | | | |
| | | 6 | aequalsb | When asserted the DACB data is driven onto DACA. | 0 | | | | | |
| | | 5 | Reserved | Reserved for factory use. | 0 | | | | | |
| | | 4 | Unused | Reserved for factory use. | 0 | | | | | |
| | | 3 | Unused | Reserved for factory use. | 0 | | | | | |
| | | 2 | Unused | Reserved for factory use. | 0 | | | | | |
| | | 1 | multi_sync_sel | Selects the signal source for multiple device and clock divider synchronization. | 0 | | | | | |
| | | | | <table border="1"> <thead> <tr> <th>multi_sync_sel</th> <th>Sync Source</th> </tr> </thead> <tbody> <tr> <td>0</td> <td>OSTR</td> </tr> <tr> <td>1</td> <td>FRAME through FIFO handoff</td> </tr> </tbody> </table> | | multi_sync_sel | Sync Source | 0 | OSTR | 1 |
| multi_sync_sel | Sync Source | | | | | | | | | |
| 0 | OSTR | | | | | | | | | |
| 1 | FRAME through FIFO handoff | | | | | | | | | |
| | | 0 | rev | Reverse the input bits for the data word. MSB becomes LSB. | 0 | | | | | |

Register name: CONFIG20 – Address: 0x14, Default = 0x00 (CAUSES AUTOSYNC)

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|------------------|--|---------------|
| CONFIG20 | 0x14 | 7:0 | qmc_offseta(7:0) | Lower 8 bits of the DAC A offset correction. The offset is measured in DAC LSBs. Writing this register causes an autosync to be generated. This loads the values of all four qmc_offset registers (CONFIG20-CONFIG23) into the offset block at the same time. When updating the offset values CONFIG20 should be written last. Programming any of the other three registers will not affect the offset setting. | 0X00 |

Register name: CONFIG21 – Address: 0x15, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|------------------|--|---------------|
| CONFIG21 | 0x15 | 7:0 | qmc_offsetb(7:0) | Lower 8 bits of the DAC B offset correction. The offset is measured in DAC LSBs. | 0X00 |

Register name: CONFIG22 – Address: 0x16, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-------------------|--|---------------|
| CONFIG22 | 0x16 | 7:3 | qmc_offseta(12:8) | Upper 5 bits of the DAC A offset correction. | 00000 |
| | | 2 | Unused | Reserved for factory use. | 0 |
| | | 1 | Unused | Reserved for factory use. | 0 |
| | | 0 | Unused | Reserved for factory use. | 0 |

Register name: CONFIG23 – Address: 0x17, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-------------------|---|---------------|
| CONFIG23 | 0x17 | 7:3 | qmc_offsetb(12:8) | Upper 5 bits of the DAC B offset correction. | 00000 |
| | | 2 | sif4_ena | When asserted the SIF interface becomes a 4 pin interface. The ALARM pin is turned into a dedicated output for the reading of data. | 0 |
| | | 1 | clkpath_sleep_a | When asserted puts the clock path through DAC A to sleep. This is useful for sleeping individual DACs. Even if the DAC is asleep the clock needs to pass through it for the logic to work. However, if the chip is being put into a power down mode, then all parts of the DAC can be turned off. | 0 |
| | | 0 | clkpath_sleep_b | When asserted puts the clock path through DAC B to sleep. | 0 |

Register name: CONFIG24 – Address: 0x18, Default = 0x83

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|---------------|---|---------------|
| CONFIG24 | 0x18 | 7 | tsense_ena | Turns on the temperature sensor when asserted. | 1 |
| | | 6 | clkrecv_sleep | When asserted the clock input receiver gets put into sleep mode. This also affects the OSTR receiver. | 0 |
| | | 5 | Unused | Reserved for factory use. | 0 |
| | | 4 | Reserved | Reserved for factory use. | 0 |
| | | 3 | sleepb | When asserted DACB is put into sleep mode. | 0 |
| | | 2 | sleepa | When asserted DACA is put into sleep mode. | 0 |
| | | 1 | Reserved | Reserved for factory use. | 1 |
| | | 0 | Reserved | Reserved for factory use. | 1 |

Register name: CONFIG25 – Address: 0x19, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|------------|--|---------------|
| CONFIG25 | 0x19 | 7:3 | Reserved | Turns on the temperature sensor when asserted. | 00000 |
| | | 2 | extref_ena | Allows the device to use an external reference or the internal reference. (0=internal, 1=external) | 0 |
| | | 1 | Reserved | Reserved for factory use. | 0 |
| | | 0 | Reserved | Reserved for factory use. | 0 |

Register name: CONFIG26 – Address: 0x1a, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------|---------------------------|---------------|
| CONFIG26 | 0x1A | 7:6 | Reserved | Reserved for factory use. | 00 |
| | | 5:4 | Reserved | Reserved for factory use. | 00 |
| | | 3 | Unused | Reserved for factory use. | 0 |
| | | 2:0 | Reserved | Reserved for factory use. | 000 |

Register name: CONFIG27 – Address: 0x1b, Default = 0x00 (CAUSES AUTOSYNC)

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------|---|---------------|
| CONFIG27 | 0x1B | 7:0 | qmc_gaina(7:0) | Lower 8 bits of the 11-bit DAC A QMC gain word. The upper 3 bits are located in the CONFIG30 register. The full 11-bit qmc_gaina(10:0) value is formatted as UNSIGNED with a range of 0 to 1.9990 and a default gain of 1. The implied decimal point for the multiplication is between bits 9 and 10. Writing this register causes an autosync to be generated. This loads the values of all four qmc_phase/gain registers (CONFIG27-CONFIG30) into the QMC block at the same time. When updating the QMC phase and/or gain values CONFIG27 should be written last. Programming any of the other three registers will not affect the QMC settings. | 0X00 |

Register name: CONFIG28 – Address: 0x1C, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------|--|---------------|
| CONFIG28 | 0x1C | 7:0 | qmc_gainb(7:0) | Lower 8 bits of the 11-bit DAC B QMC gain word. The upper 3 bits are located in the CONFIG30 register. Refer to CONFIG27 for formatting. | 0X00 |

Register name: CONFIG29 – Address: 0x1D, Default = 0x00

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|----------------|---|---------------|
| CONFIG29 | 0x1D | 7:0 | qmc_phase(7:0) | Lower 8-bits of the 10-bit QMC phase word. The upper 2 bits are in the CONFIG30 register. The full 10-bit qmc_phase(9:0) word is formatted as two's complement and scaled to occupy a range of –0.125 to 0.12475 (note this value does not correspond to degrees) and a default phase correction of 0. To accomplish QMC phase correction, this value is multiplied by the current 'Q' sample, then summed into the 'I' sample. | 0X00 |

Register name: CONFIG30 – Address: 0x1E, Default = 0x24

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|-----------------|--|---------------|
| CONFIG30 | 0x1E | 7:6 | qmc_phase(9:8) | Upper 2 bits of qmc_phase. Defaults to zero. | 00 |
| | | 5:3 | qmc_gaina(10:8) | Upper 3 bits of qmc_gaina. Defaults to unity gain. | 100 |
| | | 2:0 | qmc_gainb(10:8) | Upper 3 bits of qmc_gainb. Defaults to unity gain. | 100 |

Register name: VERSION31 – Address: 0x1F, Default = 0x52 (PARTIAL READ ONLY)

| Register Name | Address | Bit | Name | Function | Default Value |
|---------------|---------|-----|--------------|---|---------------|
| VERSION31 | 0x1F | 7 | clk_alarm | This bit is set to '1' when DATACLK is stopped for 4 clock cycles. Once set, the bit needs to be cleared by writing a '0'. | 0 |
| | | 6 | tx_off | This bit is set to '1' when the clk_alarm is triggered. When set the DAC outputs are forced to mid-level. Once set, the bit needs to be cleared by writing a '0'. | 0 |
| | | 5:0 | version(5:0) | A hardwired register that contains the version of the chip. (Read Only) | 010010 |

SERIAL INTERFACE

The serial port of the DAC3283 is a flexible serial interface which communicates with industry standard microprocessors and microcontrollers. The interface provides read/write access to all registers used to define the operating modes of DAC3283. It is compatible with most synchronous transfer formats and can be configured as a 3 or 4 pin interface by **sif4_ena** in register **CONFIG23**. In both configurations, SCLK is the serial interface input clock and SDENB is serial interface enable. For 3 pin configuration, SDIO is a bidirectional pin for both data in and data out. For 4 pin configuration, SDIO is data in only and ALARM_SDO is data out only. Data is input into the device with the rising edge of SCLK. Data is output from the device on the falling edge of SCLK.

Each read/write operation is framed by signal SDENB (Serial Data Enable Bar) asserted low for 2 to 5 bytes, depending on the data length to be transferred (1–4 bytes). The first frame byte is the instruction cycle which identifies the following data transfer cycle as read or write, how many bytes to transfer, and what address to transfer the data. [Table 2](#) indicates the function of each bit in the instruction cycle and is followed by a detailed description of each bit. Frame bytes 2 to 5 comprise the data transfer cycle.

Table 2. Instruction Byte of the Serial Interface

| | MSB | | | | LSB | | | |
|-------------|-----|----|----|----|-----|----|----|----|
| Bit | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
| Description | R/W | N1 | N0 | A4 | A3 | A2 | A1 | A0 |

R/W Identifies the following data transfer cycle as a read or write operation. A high indicates a read operation from DAC3283 and a low indicates a write operation to DAC3283.

[N1:N0] Identifies the number of data bytes to be transferred per [Table 3](#). Data is transferred MSB first.

Table 3. Number of Transferred Bytes Within One Communication Frame

| N1 | N0 | Description |
|----|----|------------------|
| 0 | 0 | Transfer 1 Byte |
| 0 | 1 | Transfer 2 Bytes |
| 1 | 0 | Transfer 3 Bytes |
| 1 | 1 | Transfer 4 Bytes |

[A4:A0] Identifies the address of the register to be accessed during the read or write operation. For multi-byte transfers, this address is the starting address. Note that the address is written to the DAC3283 MSB first and counts down for each byte.

[Figure 32](#) shows the serial interface timing diagram for a DAC3283 write operation. SCLK is the serial interface clock input to DAC3283. Serial data enable SDENB is an active low input to DAC3283. SDIO is serial data in. Input data to DAC3283 is clocked on the rising edges of SCLK.

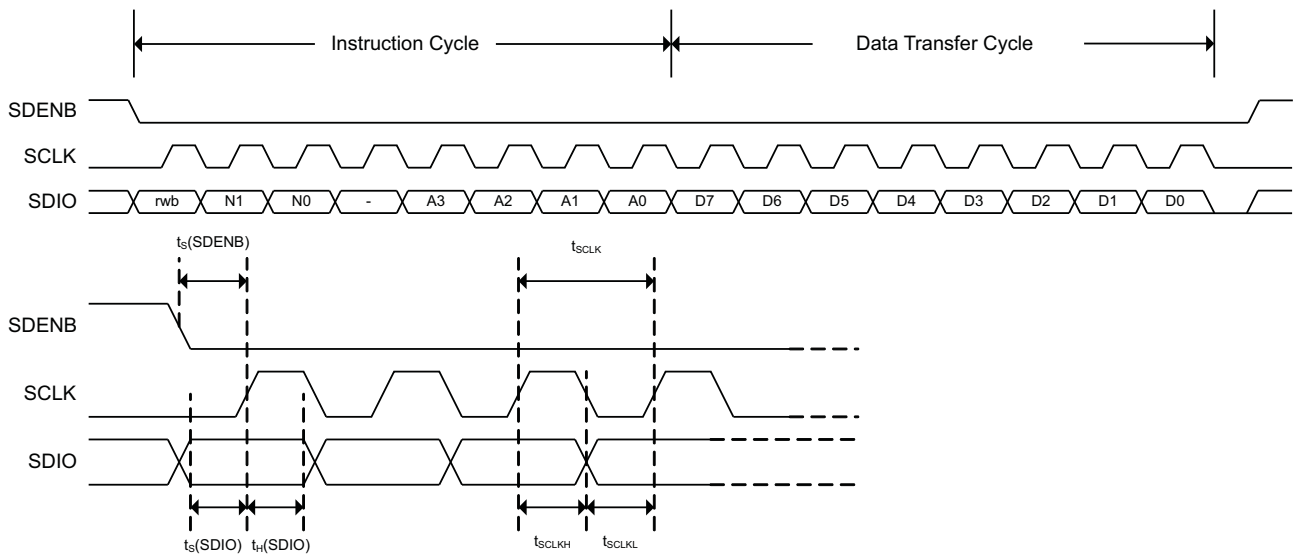


Figure 32. Serial Interface Write Timing Diagram

Figure 33 shows the serial interface timing diagram for a DAC3283 read operation. SCLK is the serial interface clock input to DAC3283. Serial data enable SDENB is an active low input to DAC3283. SDIO is serial data in during the instruction cycle. In 3 pin configuration, SDIO is data out from DAC3283 during the data transfer cycle(s), while ALARM_SDO is in a high-impedance state. In 4 pin configuration, ALARM_SDO is data out from DAC3283 during the data transfer cycle(s). At the end of the data transfer, ALARM_SDO will output low on the final falling edge of SCLK until the rising edge of SDENB when it will 3-state.

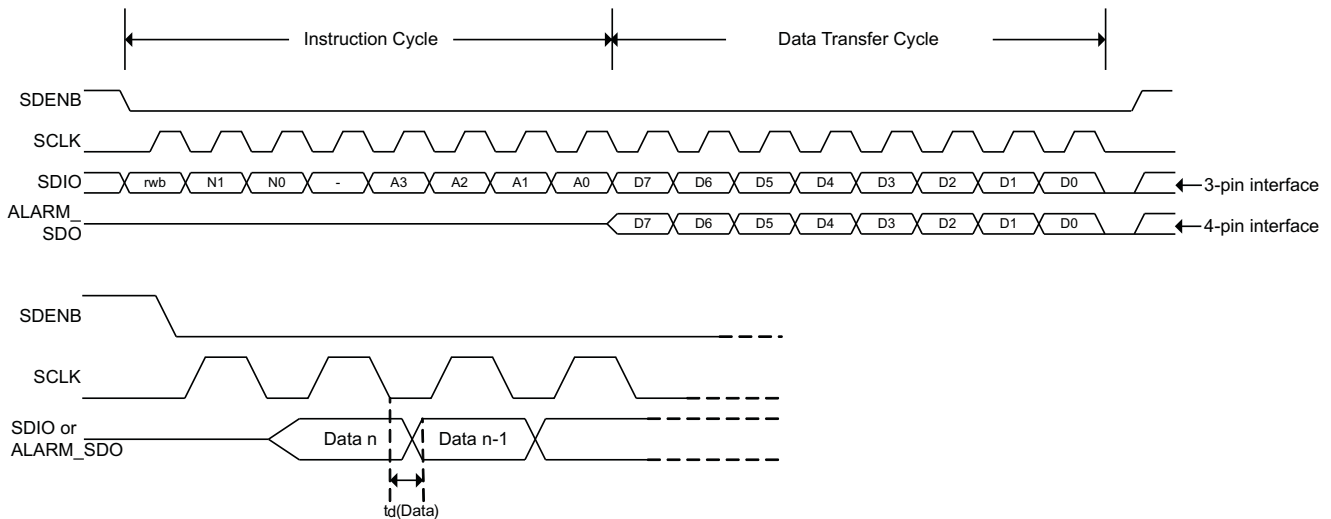


Figure 33. Serial Interface Read Timing Diagram

DATA INTERFACE

The DAC3283 has a single 8-bit LVDS bus that accepts dual, 16-bit data input in byte-wide format. Data into the DAC3283 is formatted according to the diagram shown in Figure 34 where index 0 is the data LSB and index 15 is the data MSB. The data is sampled by DATACLK, a double data rate (DDR) clock.

The FRAME signal is required to indicate the beginning of a frame. The frame signal can be either a pulse or a periodic signal where the frame period corresponds to 8 samples. The pulse-width (t_{FRAME}) needs to be at least equal to $\frac{1}{2}$ of the DATACLK period. FRAME is sampled by a rising edge in DATACLK.

The setup and hold requirements listed in the specifications tables must be met to ensure proper sampling.

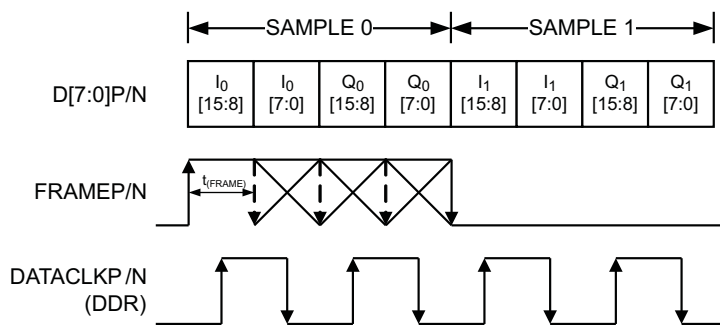


Figure 34. Byte-Wide Data Transmission Format

INPUT FIFO

The DAC3283 includes a 2-channel, 16-bits wide and 8-samples deep input FIFO which acts as an elastic buffer. The purpose of the FIFO is to absorb any timing variations between the input data and the internal DAC data rate clock such as the ones resulting from clock-to-data variations from the data source.

Figure 35 shows a simplified block diagram of the FIFO.

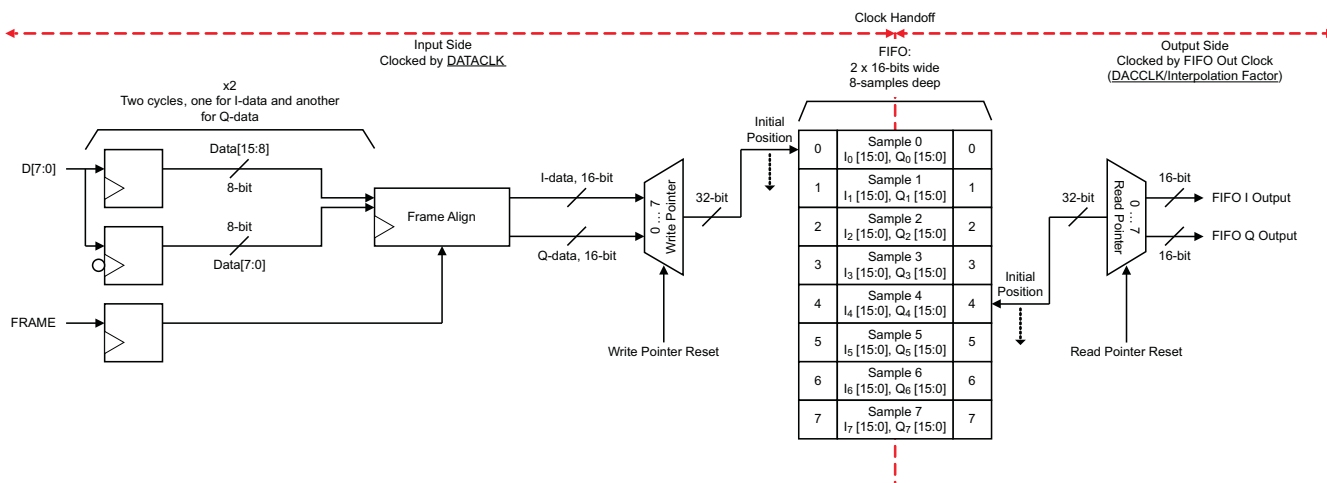


Figure 35. DAC3283 FIFO Block Diagram

Data is written to the device 8-bits at a time on the rising and falling edges of DATACLK. In order to form a complete 32-bit wide sample (16-bit I-data and 16-bit Q-data) two DATACLK periods are required as shown in Figure 36. Each 32-bit wide sample is written into the FIFO at the address indicated by the write pointer. Similarly, data from the FIFO is read by the FIFO Out Clock 32-bits at a time from the address indicated by the read pointer. The FIFO Out Clock is generated internally from the DACCLK signal and its rate is equal to DACCLK/Interpolation. Each time a FIFO write or FIFO read is done the corresponding pointer moves to the next address.

The reset position for the FIFO read and write pointers is set by default to addresses 0 and 4 as shown in [Figure 35](#). This offset gives optimal margin within the FIFO. The default read pointer location can be set to another value using `fifo_offset(2:0)` in register CONFIG3. Under normal conditions data is written-to and read-from the FIFO at the same rate and consequently the write and read pointer gap remains constant. If the FIFO write and read rates are different, the corresponding pointers will be cycling at different speeds which could result in pointer collision. Under this condition the FIFO attempts to read and write data from the same address at the same time which will result in errors and thus must be avoided.

The FRAME signal besides acting as a frame indicator can also be used to reset the FIFO pointers to their initial location. Unlike Data, the FRAME signal is latched only on the rising edges of DATACLK. When a rising edge occurs on FRAME, the pointers will return to their original position. The write pointer is always set back to position 0 upon reset. The read pointer reset position is determined by `fifo_offset` (address 4 by default).

The reset can be done periodically or only once during initialization as the pointer automatically returns to the initial position when the FIFO has been filled. To enable a single reset, `fifo_reset_ena` (CONFIG0, bit 5) must be set to 0 after initialization.

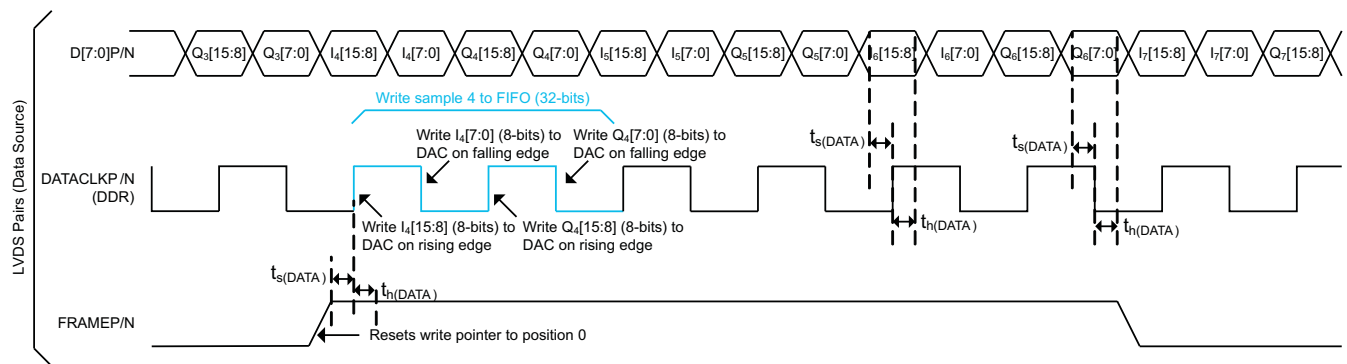


Figure 36. FIFO Write Description

FIFO ALARMS

The FIFO only operates correctly when the write and read pointers are positioned properly. If either pointer over or under runs the other, samples will be duplicated or skipped. To prevent this, register CONFIG7 can be used to track three FIFO related alarms:

- `alarm_fifo_2away`. Occurs when the pointers are within two addresses of each other.
- `alarm_fifo_1away`. Occurs when the pointers are within one address of each other.
- `alarm_fifo_collision`. Occurs when the pointers are equal to each other.

These three alarm events are generated asynchronously with respect to the clocks and can be accessed either through CONFIG7 or through the ALARM_SDO pin.

FIFO MODES OF OPERATION

The DAC3283 FIFO can be completely bypassed through register CONFIG1. The register configuration for each mode is described in [Table 4](#).

| Register | Control Bits |
|----------|---|
| CONFIG1 | <code>fifo_ena</code> , <code>fifo_reset_ena</code> , <code>multi_sync_ena</code> |

Table 4. FIFO Operation Modes

| FIFO Mode | CONFIG1FIFO Bits | | |
|-----------|-----------------------|-----------------------------|-----------------------------|
| | <code>fifo_ena</code> | <code>fifo_reset_ena</code> | <code>multi_sync_ena</code> |
| Enabled | 1 | 1 | 1 |
| Bypass | 0 | X | X |

a) Enabled Mode

This is the recommended mode of operation for the DAC3283. In FIFO enabled mode, the FIFO is active and can be reset continuously or only once during initialization. To reset only once `fifo_reset_ena` must be set to 0 after initialization.

b) Bypass Mode

In FIFO bypass mode, the FIFO block is not used. As a result the input data is handed off from the DATACLK to the DACCLK domain without any compensation. In this mode the relationship between DATACLK and DACCLK (t_{align}) is critical and used as a synchronizing mechanism for the internal logic. Due to the t_{align} constraint it is highly recommended that a clock synchronizer device such as Texas Instruments' CDCM7005 or CDCE62005 is used to provide both clock inputs. In bypass mode the pointers have no effect on the data path or handoff.

DATA PATTERN CHECKER

The DAC3283 incorporates a simple pattern checker test in order to determine errors in the data interface. The test mode is enabled by asserting `iotest_ena` in register CONFIG1. In test mode the analog outputs are deactivated regardless of the state of TXENABLE.

The data pattern key used for the test is 8 words long and is specified by the contents of `iotest_pattern[0:7]` in registers CONFIG9 through CONFIG16. The data pattern key can be modified by changing the contents of these registers.

The first word in the test frame is determined by a rising edge transition in FRAMEP/N. The test mode determines if one or more words were received incorrectly by comparing the received data against the data pattern key. The bits in `iotest_results(7:0)` in register CONFIG8 indicate which words were received incorrectly. Furthermore, an error condition will trigger the `alarm_from_iotest` bit in register CONFIG7. Once set, the `alarm_from_iotest` bit must be reset through the serial interface to allow further testing. Alternatively, the `64cnt_ena` bit in register CONFIG3 can be enabled to reset the alarms automatically after 64 good samples without the need for a SIF write to clear the alarm.

DATACLK MONITOR

The DAC3283 incorporates a clock monitor to determine if DATACLK is present. A missing DATACLK may result in unexpected DAC outputs. The clock monitor circuit issues two alarms if a missing DATACLK event is detected: `clk_alarm` (bit 7 in register VERSION31) and `tx_off` (bit 6 in register VERSION31). When `tx_off` is set the DAC3283 outputs are automatically disabled by setting data to mid-scale.

Both alarms are set by default to trigger the ALARM_SDO pin. This functionality can be disabled by masking the alarms in register CONFIG17. Once set, the alarms must be reset through the serial interface by writing a 0 to the alarm bits. The clock monitor alarms can be disabled by setting `clk_alarm_ena` or `tx_off_ena` in register CONFIG17 to 0.

The clock monitoring function is implemented as follows:

- Power up the device using the recommended power-up sequence.
- Clear `clk_alarm` and `tx_off` by writing a 1 and then a 0.
- Unmask the alarms in register CONFIG17.
- In the case of an alarm event, the ALARM_SDO pin will trigger.
- Read registers CONFIG7 and VERSION31 registers to determine which alarm triggered the ALARM_SDO pin.
- In the case `clk_alarm` and/or `tx_off` are set, a DATACLK interruption has occurred.
- Re-apply DATACLK and clear `clk_alarm` by writing 1 and then 0.
- Re-read `clk_alarm` to verify the clock loss event has not re-triggered the alarm.
- Keep clearing and reading `clk_alarm` until no error is reported.
- If enabled re-synchronize the FIFO.
- Clear the `tx_off` alarm by writing 1 and the 0. This will re-enable the DAC outputs.

FIR FILTERS

Figure 37 and Figure 38 show the magnitude spectrum response for the FIR0 and FIR1 interpolating half-band filters where f_{IN} is the input data rate to the FIR filter. Figure 39 and Figure 40 show the composite filter response for 2x and 4x interpolation. The transition band for all the interpolation settings is from 0.4 to 0.6 \times f_{DATA} (the input data rate to the device) with $< 0.002\text{dB}$ of pass-band ripple and $> 85\text{dB}$ stop-band attenuation.

The filter taps for all digital filters are listed in Table 5.

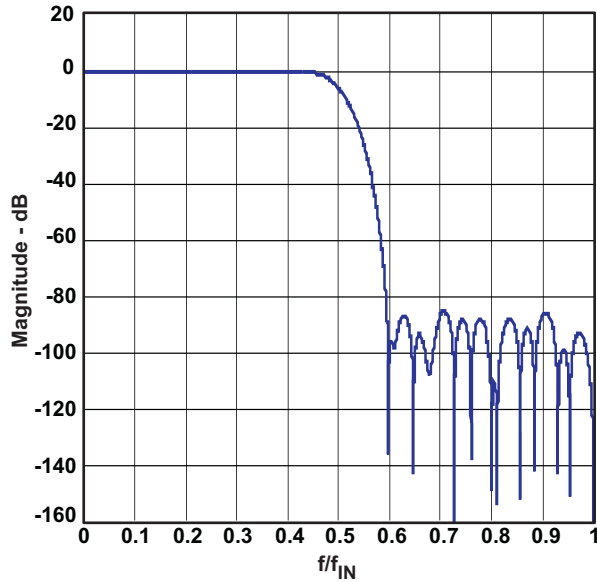


Figure 37. Magnitude Spectrum for FIR0

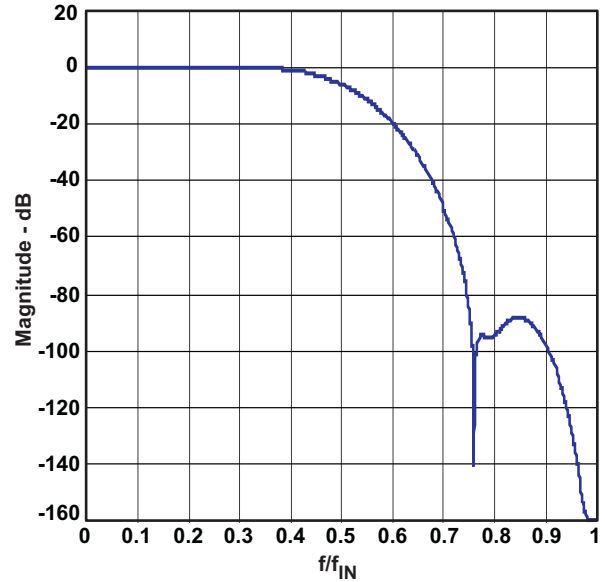


Figure 38. Magnitude Spectrum for FIR1

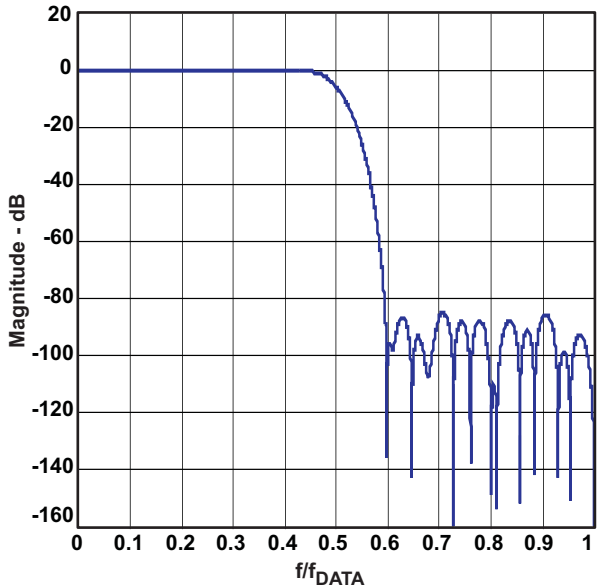


Figure 39. 2x Interpolation Composite Response

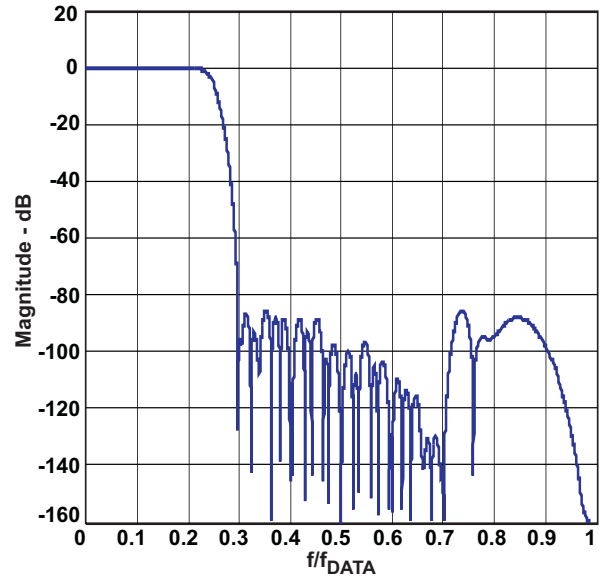


Figure 40. 4x Interpolation Composite Response

Table 5. FIR Filter Coefficients

| FIR0 2x Interpolating Half-band Filter | | FIR1 2x Interpolating Half-Band Filter |
|--|-------|--|
| 59 Taps | | 23 Taps |
| 4 | 4 | -2 |
| 0 | 0 | 0 |
| -12 | -12 | 17 |
| 0 | 0 | 0 |
| 28 | 28 | -75 |
| 0 | 0 | 0 |
| -58 | -58 | 238 |
| 0 | 0 | 0 |
| 108 | 108 | -660 |
| 0 | 0 | 0 |
| -188 | -188 | 2530 |
| 0 | 0 | 4096⁽¹⁾ |
| 308 | 308 | 2530 |
| 0 | 0 | 0 |
| -483 | -483 | -660 |
| 0 | 0 | 0 |
| 734 | 734 | 238 |
| 0 | 0 | 0 |
| -1091 | -1091 | -75 |
| 0 | 0 | 0 |
| 1607 | 1607 | 17 |
| 0 | 0 | 0 |
| -2392 | -2392 | -2 |
| 0 | 0 | |
| 3732 | 3732 | |
| 0 | 0 | |
| -6681 | -6681 | |
| 0 | 0 | |
| 20768 | 20768 | |
| 32768⁽¹⁾ | | |

(1) Center taps are highlighted in **BOLD**.

COARSE MIXER

The DAC3283 has a coarse mixer block capable of shifting the input signal spectrum by the fixed mixing frequencies $f_s/2$ or $f_s/4$. The coarse mixing function is built into the interpolation filters and thus FIR0 (2x interpolation) or FIR0 and FIR1 (4x interpolation) must be enabled to use it.

Treating channels A and B as a complex vector of the form $I(t) + j Q(t)$, where $I(t) = A(t)$ and $Q(t) = B(t)$, the outputs of the coarse mixer, $A_{OUT}(t)$ and $B_{OUT}(t)$ are equivalent to:

$$A_{OUT}(t) = A(t)\cos(2\pi f_{CMIX}t) - B(t)\sin(2\pi f_{CMIX}t)$$

$$B_{OUT}(t) = A(t)\sin(2\pi f_{CMIX}t) + B(t)\cos(2\pi f_{CMIX}t)$$

where f_{CMIX} is the fixed mixing frequency selected by `mixer_func(1:0)`. For $f_s/2$, $+f_s/4$ and $-f_s/4$ the above operations result in the simple mixing sequences shown in [Table 6](#).

Table 6. Coarse Mixer Sequences

| Mode | mixer_func(1:0) | Mixing Sequence |
|------------------------------|-----------------|--|
| Normal (Low Pass, No Mixing) | 00 | A _{OUT} = { +A, +A, +A, +A } B _{OUT} = { +B, +B, +B, +B } |
| $f_s/2$ | 01 | A _{OUT} = { +A, -A, +A, -A } B _{OUT} = { +B, -B, +B, -B } |
| $+f_s/4$ | 10 | A _{OUT} = { +A, -B, -A, +B } B _{OUT} = { +B, +A, -B, -A } |
| $-f_s/4$ | 11 | A _{OUT} = { +A, +B, -A, -B } B _{OUT} = { +B, -A, -B, +A } |

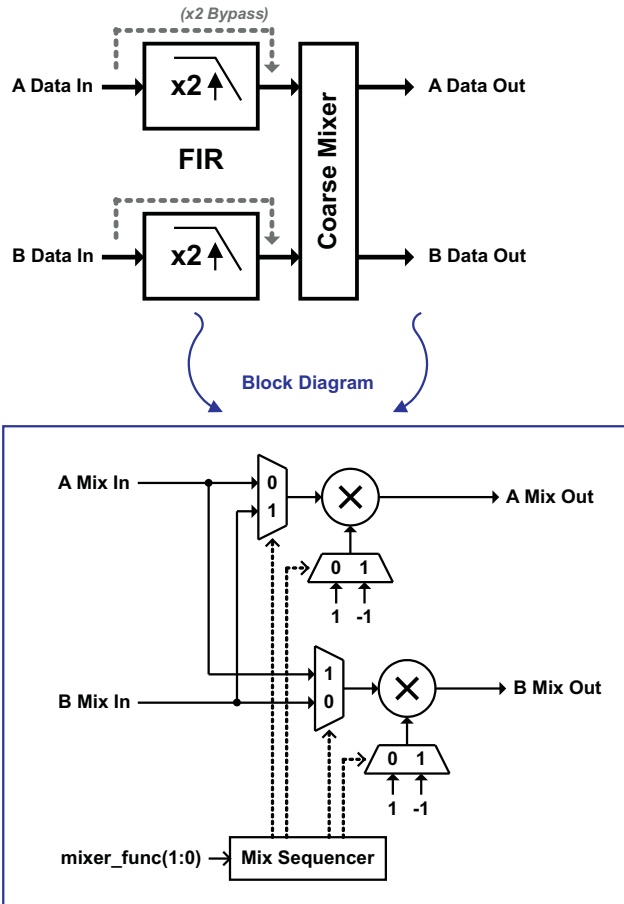


Figure 41. Coarse Mixers Block Diagram

The coarse mixer in the DAC3283 treats the A and B inputs as complex input data and for most mixing frequencies produces a complex output. Only when the mixing frequency is set to $f_s/2$ the A and B channels can be maintained isolated as shown in Table 6. In this case the two channels are upconverted as independent signals. By setting the mixer to $f_s/2$ the interpolation filter outputs are inverted thus behaving as a high-pass filter.

Table 7. Dual-Channel Real Upconversion Options

| FIR MODE | INPUT FREQUENCY ⁽¹⁾ | OUTPUT FREQUENCY ⁽¹⁾ | SIGNAL BANDWIDTH ⁽¹⁾ | SPECTRUM INVERTED? |
|-----------|--------------------------------|---------------------------------|---------------------------------|--------------------|
| Low Pass | 0.0 to $0.4 \times f_{DATA}$ | 0.0 to $0.4 \times f_{DATA}$ | $0.4 \times f_{DATA}$ | No |
| High Pass | 0.0 to $0.4 \times f_{DATA}$ | 0.6 to $1.0 \times f_{DATA}$ | $0.4 \times f_{DATA}$ | Yes |

(1) f_{DATA} is the input data rate of each channel after de-interleaving.

QUADRATURE MODULATION CORRECTION (QMC)

The Quadrature Modulator Correction (QMC) block provides a means for adjusting the gain and phase of the complex signal. At a quadrature modulator output, gain and phase imbalances result in an undesired sideband signal.

The block diagram for the QMC is shown in Figure 42. The QMC block contains 3 programmable parameters: `qmc_gaina(10:0)`, `qmc_gainb(10:0)` and `qmc_phase(9:0)`.

Registers `qmc_gaina(10:0)` and `qmc_gainb(10:0)` control the I and Q path gains and are 11 bit values with a range of 0 to approximately 2. This value is used to scale the signal range. Register `qmc_phase(9:0)` controls the phase imbalance between I and Q and is a 10-bit value that ranges from $-1/8$ to approximately $+1/8$. This value is multiplied by each Q sample then summed into the I sample path. This operation is a simplified approximation of a true phase rotation and covers the range from -3.75 to $+3.75$ degrees in 1024 steps.

A write to register CONFIG27 is required to load the gain and phase values (CONFIG27-CONFIG30) into the QMC block simultaneously. When updating the gain and/or phase values CONFIG27 should be written last. Programming any of the other three registers will not affect the gain and phase settings.

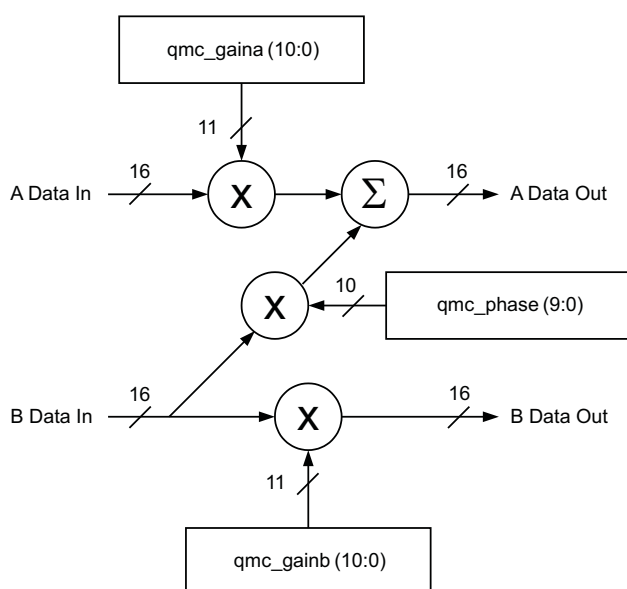


Figure 42. QMC Block Diagram

DIGITAL OFFSET CONTROL

The `qmc_offseta(12:0)` and `qmc_offsetb(12:0)` values in registers CONFIG20 through CONFIG23 can be used to independently adjust the A and B path DC offsets. Both offset values are represented in 2s-complement format with a range from -4096 to 4095 .

Note that a write to register CONFIG20 is required to load the values of all four `qmc_offset` registers (CONFIG20-CONFIG23) into the offset block simultaneously. When updating the offset values CONFIG20 should be written last. Programming any of the other three registers will not affect the offset setting.

The offset value adds a digital offset to the digital data before digital-to-analog conversion. Since the offset is added directly to the data it may be necessary to back off the signal to prevent saturation. Both data and offset values are LSB aligned.

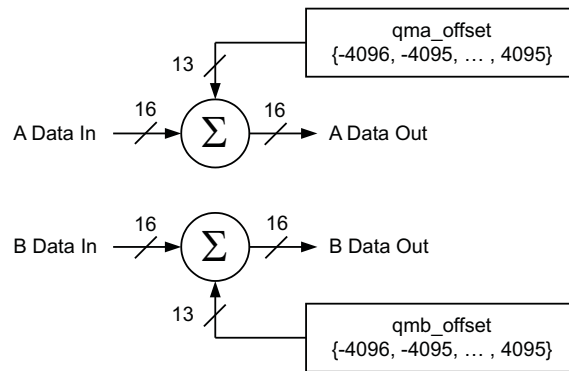


Figure 43. Digital Offset Block Diagram

TEMPERATURE SENSOR

The DAC3283 incorporates a temperature sensor block which monitors the temperature by measuring the voltage across 2 transistors. The voltage is converted to an 8-bit digital word using a successive-approximation (SAR) analog to digital conversion process. The result is scaled, limited and formatted as a two's complement value representing the temperature in degrees Celsius.

The sampling is controlled by the serial interface signals SDENB and SCLK. If the temperature sensor is enabled (`tsense_ena = 1` in register CONFIG24) a conversion takes place each time the serial port is written or read. The data is only read and sent out by the digital block when the temperature sensor is read in register CONFIG5. The conversion uses the first eight clocks of the serial clock as the capture and conversion clock, the data is valid on the falling eighth SCLK. The data is then clocked out of the chip on the rising edge of the ninth SCLK. No other clocks to the chip are necessary for the temperature sensor operation. As a result the temperature sensor is enabled even when the device is in sleep mode.

In order for the process described above to operate properly, the serial port read from CONFIG5 must be done with an SCLK period of at least 1 μ s. If this is not satisfied the temperature sensor accuracy is greatly reduced.

POWER-UP SEQUENCE

The following startup sequence is recommended to power-up the DAC3283:

- Set TXENABLE low.
- Supply 1.8V to DACVDD18, DIGVDD18, CLKVDD18 and VFUSE simultaneously and 3.3V to AVDD33. Within AVDD33 the multiple AVDD33 pins should be powered up simultaneously. The 1.8V and 3.3V supplies can be powered up simultaneously or in any order.
There are no specific requirements on the ramp rate for the supplies.
- Provide all LVPECL inputs: DACCLKP/N and if used OSTRP/N.
- Program the SIF registers.
- Provide all LVDS inputs (D[7:0]P/N, DATACLKP/N and FRAMEP/N) simultaneously.
- Sync the clock dividers and FIFO. After a FRAMEP/N low-to-high transition, clock divider syncing must be disabled by setting `clkdiv_sync_ena` (CONFIG18, bit 1) to 0. Optionally, disable FIFO syncing by setting `fifo_reset_ena` (CONFIG0, bit 5) and `multi_sync_ena` (CONFIG0, bit 4) to 0. Except when in Multi-DAC operation it is recommended to sync the DACs and their FIFO's only once during initialization.
- Enable transmit of data by asserting the TXENABLE pin.

SLEEP MODES

The DAC3283 features independent sleep control of each DAC (`sleepa` and `sleepb`), their corresponding clock path (`clkpath_sleep_a` and `clkpath_sleep_b`) as well as the clock input receiver of the device (`clkrecv_sleep`). The sleep control of each of these components is done through the SIF interface and is enabled by setting a 1 to the corresponding sleep register.

Complete power down of the device is set by setting all of these components to sleep. Under this mode the supply power consumption is reduced to 15mW. Power-up time in this case will be in the milliseconds range. Alternatively for those applications where power-up and power-down times are critical it is recommended to only set the DACs to sleep through the sleepa and sleepb registers. In this case both the sleep and wake-up times are only 90µs.

LVPECL INPUTS

Figure 44 shows an equivalent circuit for the DAC input clock (DACCLP/N) and the output strobe clock (OSTRP/N).

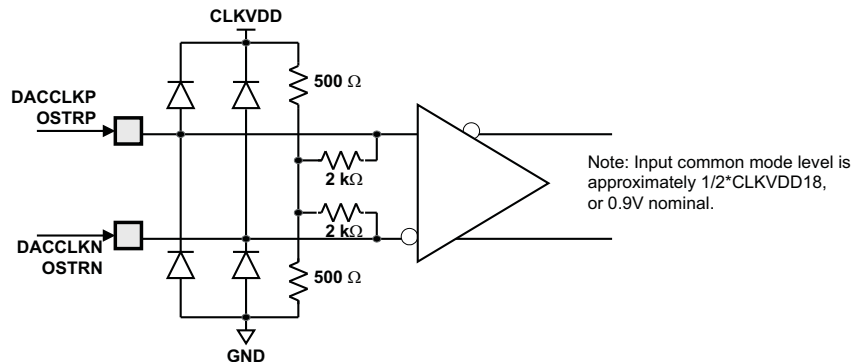


Figure 44. DACCLP/N and OSTRP/N Equivalent Input Circuit

Figure 45 shows the preferred configuration for driving the CLKIN/CLKINC input clock with a differential ECL/PECL source.

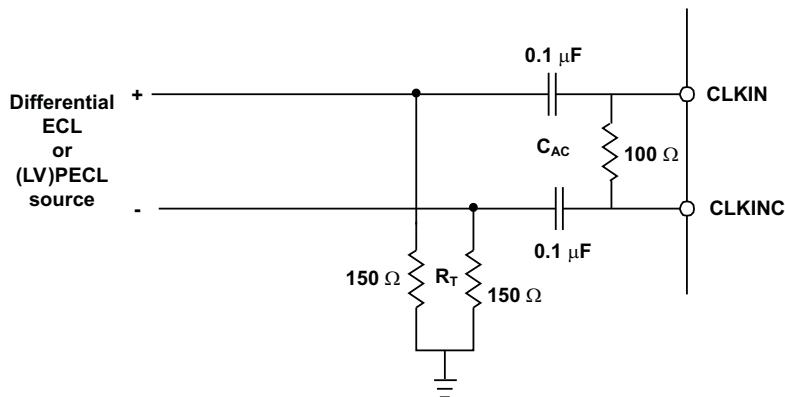


Figure 45. Preferred Clock Input Configuration with a Differential ECL/PECL Clock Source

LVDS INPUTS

The D[7:0]P/N, DATACLKP/N and FRAMEP/N LVDS pairs have the input configuration shown in Figure 46. Figure 47 shows the typical input levels and common-mode voltage used to drive these inputs.

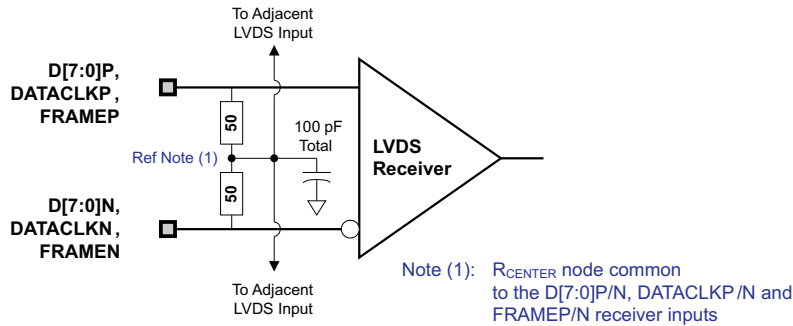


Figure 46. D[7:0]P/N, DATACLKP/N and FRAMEP/N LVDS Input Configuration

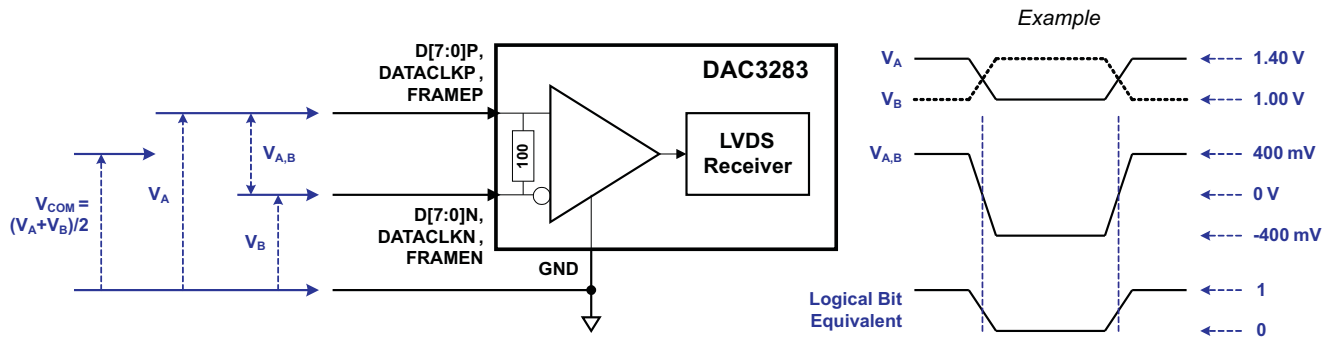


Figure 47. LVDS Data (D[7:0]P/N, DATACLKP/N, FRAMEP/N Pairs) Input Levels

Table 8. Example LVDS Data Input Levels

| APPLIED VOLTAGES | | RESULTING DEFERENTIAL VOLTAGE | RESULTING COMMON-MODE VOLTAGE | LOGICAL BIT BINARY EQUIVALENT |
|------------------|----------------|-------------------------------|-------------------------------|-------------------------------|
| V _A | V _B | V _{A,B} | V _{COM} | |
| 1.4 V | 1.0 V | 400 mV | 1.2 V | 1 |
| 1.0 V | 1.4 V | -400 mV | | 0 |
| 1.2 V | 0.8 V | 400 mV | 1.0 V | 1 |
| 0.8 V | 1.2 V | -400 mV | | 0 |

CMOS DIGITAL INPUTS

Figure 48 shows a schematic of the equivalent CMOS digital inputs of the DAC3283. SDIO, SCLK and TXENABLE have pull-down resistors while SDENB has a pull-up resistors internal to the DAC3283. See the specification table for logic thresholds. The pull-up and pull-down circuitry is approximately equivalent to 100kΩ.

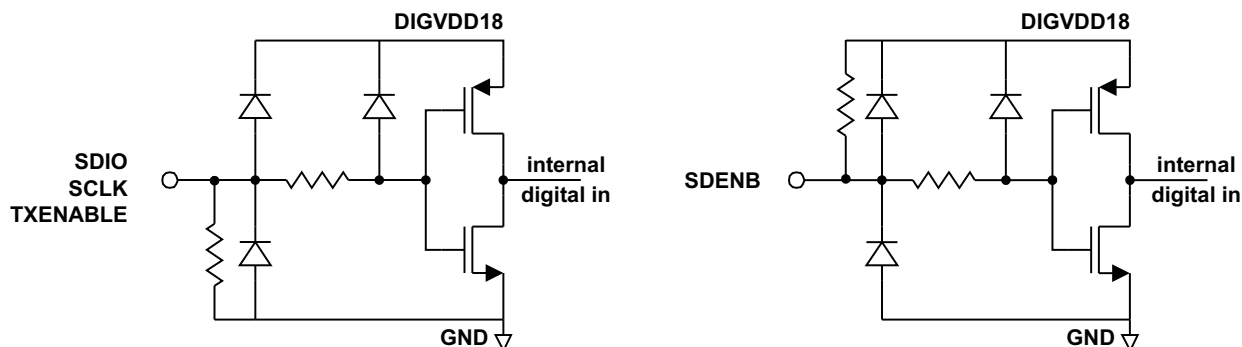


Figure 48. CMOS/TTL Digital Equivalent Input

REFERENCE OPERATION

The DAC3283 uses a bandgap reference and control amplifier for biasing the full-scale output current. The full-scale output current is set by applying an external resistor R_{BIAS} to pin BIASJ. The bias current I_{BIAS} through resistor R_{BIAS} is defined by the on-chip bandgap reference voltage and control amplifier. The default full-scale output current equals 16 times this bias current and can thus be expressed as:

$$I_{OUTFS} = 16 \times I_{BIAS} = 16 \times V_{EXTIO} / R_{BIAS}$$

Each DAC has a 4-bit coarse gain control via **coarse_daca(3:0)** and **coarse_dacb (3:0)** in the CONFIG4 register. Using gain control, the I_{OUTFS} can be expressed as:

$$I_{OUTAFS} = (DACA_gain + 1) \times I_{BIAS} = (DACA_gain + 1) \times V_{EXTIO} / R_{BIAS}$$

$$I_{OUTBFS} = (DACB_gain + 1) \times I_{BIAS} = (DACB_gain + 1) \times V_{EXTIO} / R_{BIAS}$$

where V_{EXTIO} is the voltage at terminal EXTIO. The bandgap reference voltage delivers an accurate voltage of 1.2V. This reference is active when **extref_ena** = '0' in CONFIG25. An external decoupling capacitor C_{EXT} of 0.1μF should be connected externally to terminal EXTIO for compensation. The bandgap reference can additionally be used for external reference operation. In that case, an external buffer with high impedance input should be applied in order to limit the bandgap load current to a maximum of 100nA. The internal reference can be disabled and overridden by an external reference by setting the CONFIG25 **extref_ena** control bit. Capacitor C_{EXT} may hence be omitted. Terminal EXTIO thus serves as either input or output node.

The full-scale output current can be adjusted from 20mA down to 2mA by varying resistor R_{BIAS} or changing the externally applied reference voltage. The internal control amplifier has a wide input range, supporting the full-scale output current range of 20dB.

DAC TRANSFER FUNCTION

The CMOS DAC's consist of a segmented array of NMOS current sinks, capable of sinking a full-scale output current up to 20mA. Differential current switches direct the current to either one of the complementary output nodes IOUT1 or IOUT2. (DACA = IOUTA1 or IOUTA2 and DACB = IOUTB1 or IOUTB2.) Complementary output currents enable differential operation, thus canceling out common mode noise sources (digital feed-through, on-chip and PCB noise), dc offsets, even order distortion components, and increasing signal output power by a factor of two.

The full-scale output current is set using external resistor R_{BIAS} in combination with an on-chip bandgap voltage reference source (+1.2V) and control amplifier. Current I_{BIAS} through resistor R_{BIAS} is mirrored internally to provide a maximum full-scale output current equal to 16 times I_{BIAS} .

The relation between IOUT1 and IOUT2 can be expressed as:

$$I_{OUT1} = - I_{OUTFS} - I_{OUT2}$$

Current flowing into a node is denoted as – current and current flowing out of a node as + current. Since the output stage is a current sink the current can only flow from AVDD into the IOUT1 and IOUT2 pins. The output current flow in each pin driving a resistive load can be expressed as:

$$IOUT1 = IOUTFS \times (65535 - CODE) / 65536$$

$$IOUT2 = IOUTFS \times CODE / 65536$$

where CODE is the decimal representation of the DAC data input word.

For the case where IOUT1 and IOUT2 drive resistor loads R_L directly, this translates into single ended voltages at IOUT1 and IOUT2:

$$VOUT1 = AVDD - |IOUT1| \times R_L$$

$$VOUT2 = AVDD - |IOUT2| \times R_L$$

Assuming that the data is full scale (65536 in offset binary notation) and the R_L is 25 Ω , the differential voltage between pins IOUT1 and IOUT2 can be expressed as:

$$VOUT1 = AVDD - |-0 \text{ mA}| \times 25 \Omega = 3.3 \text{ V}$$

$$VOUT2 = AVDD - |-20 \text{ mA}| \times 25 \Omega = 2.8 \text{ V}$$

$$VDIFF = VOUT1 - VOUT2 = 0.5 \text{ V}$$

Note that care should be taken not to exceed the compliance voltages at node IOUT1 and IOUT2, which would lead to increased signal distortion.

ANALOG CURRENT OUTPUTS

Figure 49 shows a simplified schematic of the current source array output with corresponding switches. Differential switches direct the current of each individual NMOS current source to either the positive output node IOUT1 or its complementary negative output node IOUT2. The output impedance is determined by the stack of the current sources and differential switches, and is typically >300 k Ω in parallel with an output capacitance of 5 pF.

The external output resistors are referenced to an external ground. The minimum output compliance at nodes IOUT1 and IOUT2 is limited to $AVDD - 0.5 \text{ V}$, determined by the CMOS process. Beyond this value, transistor breakdown may occur resulting in reduced reliability of the DAC3283 device. The maximum output compliance voltage at nodes IOUT1 and IOUT2 equals $AVDD + 0.5 \text{ V}$. Exceeding the minimum output compliance voltage adversely affects distortion performance and integral non-linearity. The optimum distortion performance for a single-ended or differential output is achieved when the maximum full-scale signal at IOUT1 and IOUT2 does not exceed 0.5 V.

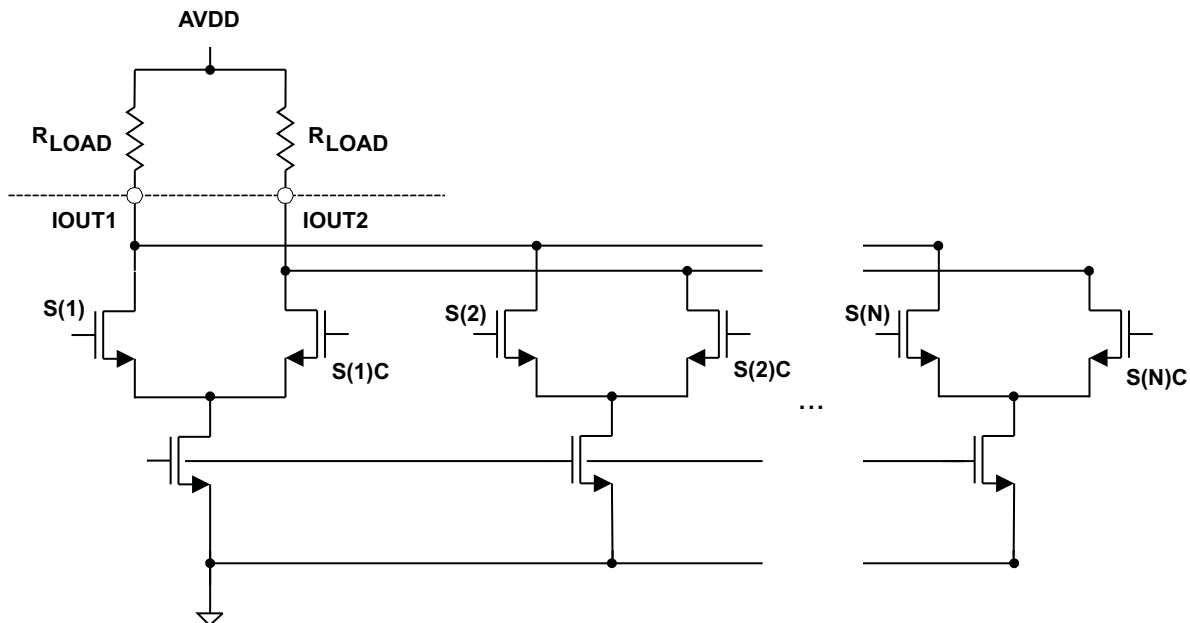


Figure 49. Equivalent Analog Current Output

The DAC3283 can be easily configured to drive a doubly terminated 50Ω cable using a properly selected RF transformer. Figure 50 and Figure 51 show the 50Ω doubly terminated transformer configuration with 1:1 and 4:1 impedance ratio, respectively. Note that the center tap of the primary input of the transformer has to be connected to AVDD to enable a dc current flow. Applying a 20 mA full-scale output current would lead to a 0.5 V_{PP} for a 1:1 transformer, and a 1 V_{PP} output for a 4:1 transformer. The low dc-impedance between IOUT1 or IOUT2 and the transformer center tap sets the center of the ac-signal at AVDD, so the 1 V_{PP} output for the 4:1 transformer results in an output between AVDD + 0.5 V and AVDD – 0.5 V.

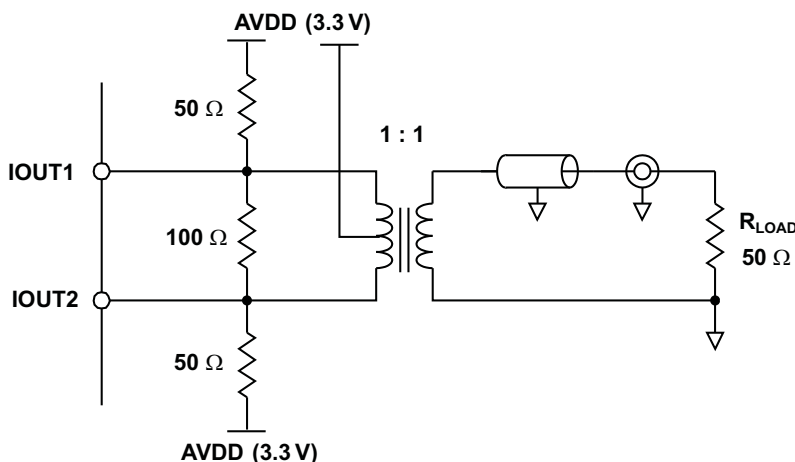


Figure 50. Driving a Doubly-Terminated 50-Ω Cable Using a 1:1 Impedance Ratio Transformer

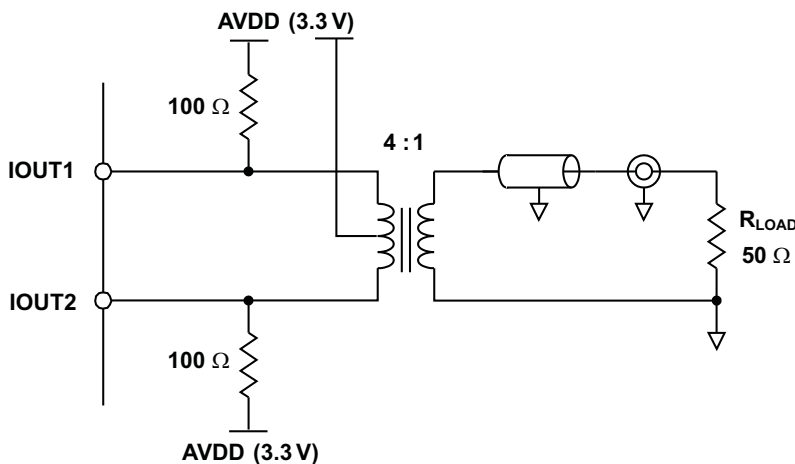


Figure 51. Driving a Doubly-Terminated 50-Ω Cable Using a 4:1 Impedance Ratio Transformer

PASSIVE INTERFACE TO ANALOG QUADRATURE MODULATORS

A common application in communication systems is to interface the DAC to an IQ modulator like the TRF3703 family of modulators from Texas Instruments. The input of the modulator is generally of high impedance and requires a specific common-mode voltage. A simple resistive network can be used to maintain 50Ω load impedance for the DAC3283 and also provide the necessary common-mode voltages for both the DAC and the modulator.

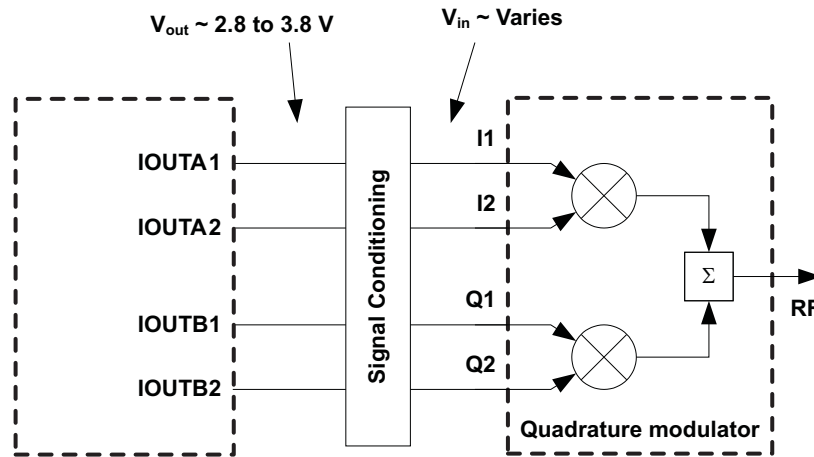


Figure 52. DAC to Analog Quadrature Modulator Interface

The DAC3283 has a maximum 20mA full-scale output and a voltage compliance range of $AV_{DD} \pm 0.5$ V. The TRF3703 IQ modulator family can be operated at three common-mode voltages: 1.5V, 1.7V, and 3.3V.

Figure 53 shows the recommended passive network to interface the DAC3283 to the TRF3703-17 which has a common mode voltage of 1.7V. The network generates the 3.3V common mode required by the DAC output and 1.7V at the modulator input, while still maintaining 50Ω load for the DAC.

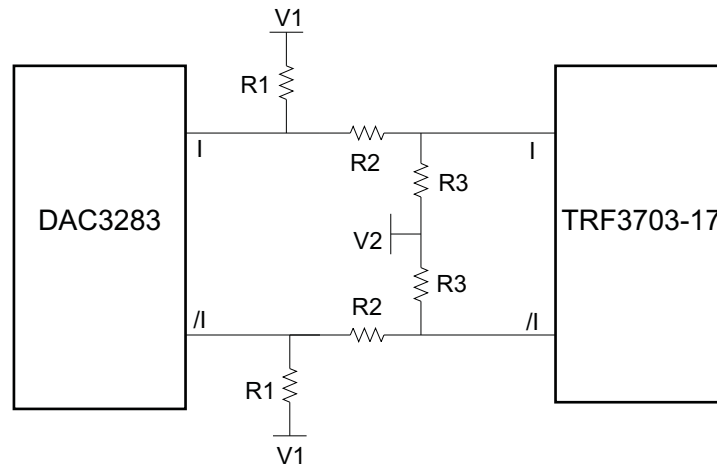


Figure 53. DAC3283 to TRF3703-17 Interface

If V_1 is set to 5V and V_2 is set to -5V, the corresponding resistor values are $R_1 = 57\Omega$, $R_2 = 80\Omega$, and $R_3 = 336\Omega$. The loss developed through R_2 is about -1.86 dB. In the case where there is no -5V supply available and V_2 is set to 0V, the resistor values are $R_1 = 66\Omega$, $R_2 = 101\Omega$, and $R_3 = 107\Omega$. The loss with these values is -5.76dB.

Figure 54 shows the recommended network for interfacing with the TRF3703-33 which requires a common mode of 3.3V. This is the simplest interface as there is no voltage shift. Because there is no voltage shift there is any loss in the network. With $V_1 = 5V$ and $V_2 = 0V$, the resistor values are $R_1 = 66\Omega$ and $R_3 = 208\Omega$.

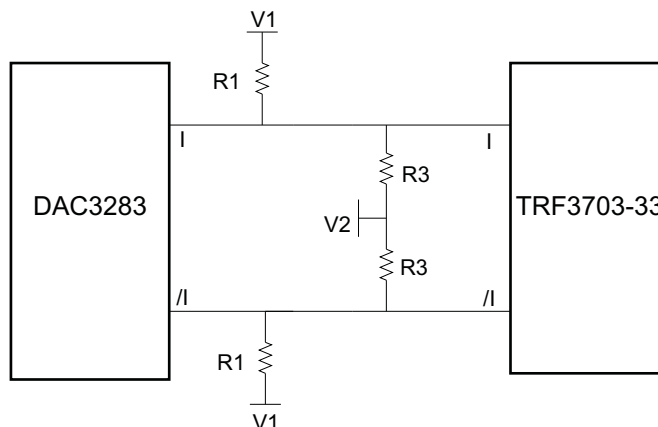


Figure 54. DAC3283 to TRF3703-33 Interface

In most applications a baseband filter is required between the DAC and the modulator to eliminate the DAC images. This filter can be placed after the common-mode biasing network. For the DAC to modulator network shown in Figure 55, R2 and the filter load R4 need to be considered into the DAC impedance. The filter has to be designed for the source impedance created by the resistor combination of $R3 \parallel (R2+R1)$. The effective impedance seen by the DAC is affected by the filter termination resistor resulting in $R1 \parallel (R2+R3 \parallel (R4/2))$.

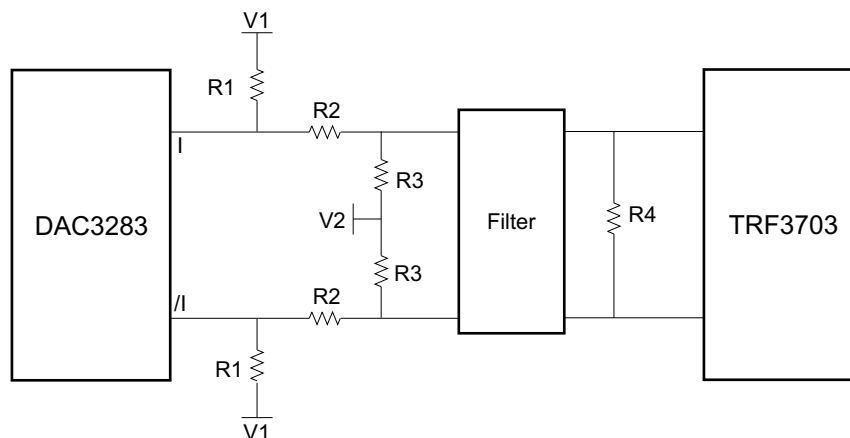


Figure 55. DAC3283 to Modulator Interface with Filter

Factoring in R4 into the DAC load, a typical interface to the TRF3703-17 with V1 = 5V and V2 = 0V results in the following values: R1 = 72Ω, R2 = 116Ω, R3 = 124Ω and R4 = 150Ω. This implies that the filter needs to be designed for 75Ω input and output impedance (single-ended impedance). The common mode levels for the DAC and modulator are maintained at 3.3V and 1.7V and the DAC load is 50Ω. The added load of the filter termination causes the signal to be attenuated by -10.8 dB.

A filter can be implemented in a similar manner to interface with the TRF3703-33. In this case it is much simpler to balance the loads and common mode voltages due to the absence of R2. An added benefit is that there is no loss in this network. With V1 = 5V and V2 = 0V the network can be designed such that R1 = 115Ω, R3 = 681Ω, and R4 = 200Ω. This results in a filter impedance of $R1 \parallel R2=100\Omega$, and a DAC load of $R1 \parallel R3 \parallel (R4/2)$ which is equal to 50Ω. R4 is a differential resistor and does not affect the common mode level created by R1 and R3. The common-mode voltage is set at 3.3 V for a full-scale current of 20mA.

For more information on how to interface the DAC3283 to an analog quadrature modulator please refer to the application reports *Passive Terminations for Current Output DACs* (SLAA399) and *Design of Differential Filters for High-Speed Signal Chains* (SLWA053).

APPLICATION INFORMATION

DIRECT CONVERSION RADIO

Refer to [Figure 56](#) for an example Direct Conversion Radio. The DAC3283 receives an interleaved complex I/Q baseband input data stream and increases the sample rate through interpolation by a factor of 2 or 4. By performing digital interpolation on the input data, undesired images of the original signal can be pushed out of the band of interest and more easily suppressed with analog filters.

For a Zero IF (ZIF) frequency plan, complex mixing of the baseband signal is not required. Alternatively, for a Complex IF frequency plan the input data can be pre-placed at an IF within the bandwidth limitations of the interpolation filters. In addition, complex mixing is available using the coarse mixer block to up-convert the signal. The output of both DAC channels is used to produce a Hilbert transform pair and can be expressed as:

$$A_{OUT}(t) = A(t)\cos(\omega_c t) - B(t)\sin(\omega_c t) = m(t)$$

$$B_{OUT}(t) = A(t)\sin(\omega_c t) + B(t)\cos(\omega_c t) = m_h(t)$$

where $m(t)$ and $m_h(t)$ connote a Hilbert transform pair and ω_c is the mixer frequency. The complex output is input to an analog quadrature modulator (AQM) such as the Texas Instruments TRF3720 for a single side-band (SSB) up conversion to RF. A passive (resistor only) interface to the AQM with an optional LC filter network is recommended. The TRF3720 includes a VCO/PLL to generate the LO frequency. Upper single-sideband upconversion is achieved at the output of the analog quadrature modulator, whose output is expressed as:

$$RF(t) = A(t)\cos(\omega_c + \omega_{LO})t - B(t)\sin(\omega_c + \omega_{LO})t$$

Flexibility is provided to the user by allowing for the selection of negative mixing frequency to produce a lower-sideband upconversion. Note that the process of complex mixing translates the signal frequency from 0Hz means that the analog quadrature modulator IQ imbalance produces a sideband that falls outside the signal of interest. DC offset error in DAC and AQM signal path may produce LO feed-through at the RF output which may fall in the band of interest. To suppress the LO feed-through, the DAC3283 provides a digital offset correction capability for both DAC-A and DAC-B paths. In addition phase and gain imbalances in the DAC and AQM result in a lower-sideband product. The DAC3283 offers gain and phase correction capabilities to minimize the sideband product.

The complex IF architecture has several advantages over the real IF architecture:

- Uncalibrated side-band suppression ~ 35dBc compared to 0dBc for real IF architecture.
- Direct DAC to AQM interface – no amplifiers required
- DAC 2nd Nyquist zone image is offset f_{DAC} compared with $f_{DAC} - 2 \times IF$ for a real IF architecture, reducing the need for filtering at the DAC output.
- Uncalibrated LO feed through for AQM is ~ 35dBc and calibration can reduce or completely remove the LO feed through.

APPLICATION INFORMATION (continued)

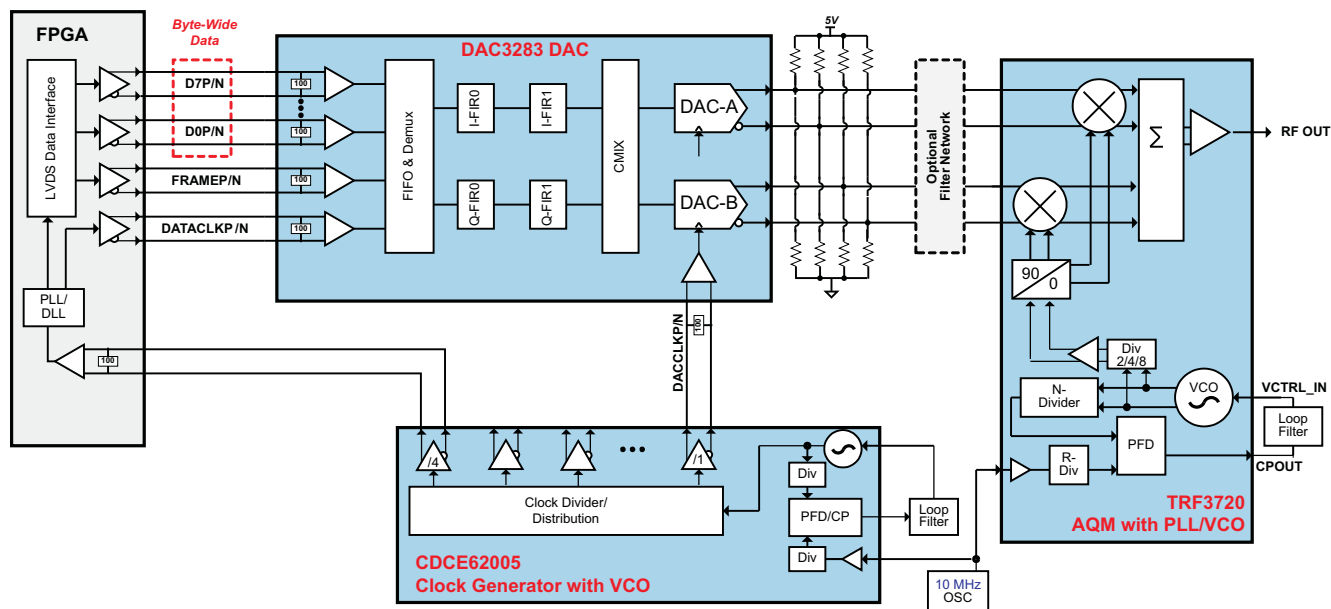


Figure 56. System Diagram of Direct Conversion Radio

PACKAGING INFORMATION

| Orderable Device | Status ⁽¹⁾ | Package Type | Package Drawing | Pins | Package Qty | Eco Plan ⁽²⁾ | Lead/Ball Finish | MSL Peak Temp ⁽³⁾ |
|------------------|-----------------------|--------------|-----------------|------|-------------|-------------------------|------------------|------------------------------|
| DAC3283IRGZR | ACTIVE | VQFN | RGZ | 48 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| DAC3283IRGZT | ACTIVE | VQFN | RGZ | 48 | 250 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBsolete: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



| | |
|----|---|
| A0 | Dimension designed to accommodate the component width |
| B0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

TAPE AND REEL INFORMATION

*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|--------------|--------------|-----------------|------|------|--------------------|--------------------|---------|---------|---------|---------|--------|---------------|
| DAC3283IRGZR | VQFN | RGZ | 48 | 2500 | 330.0 | 16.4 | 7.3 | 7.3 | 1.5 | 12.0 | 16.0 | Q2 |
| DAC3283IRGZT | VQFN | RGZ | 48 | 250 | 330.0 | 16.4 | 7.3 | 7.3 | 1.5 | 12.0 | 16.0 | Q2 |

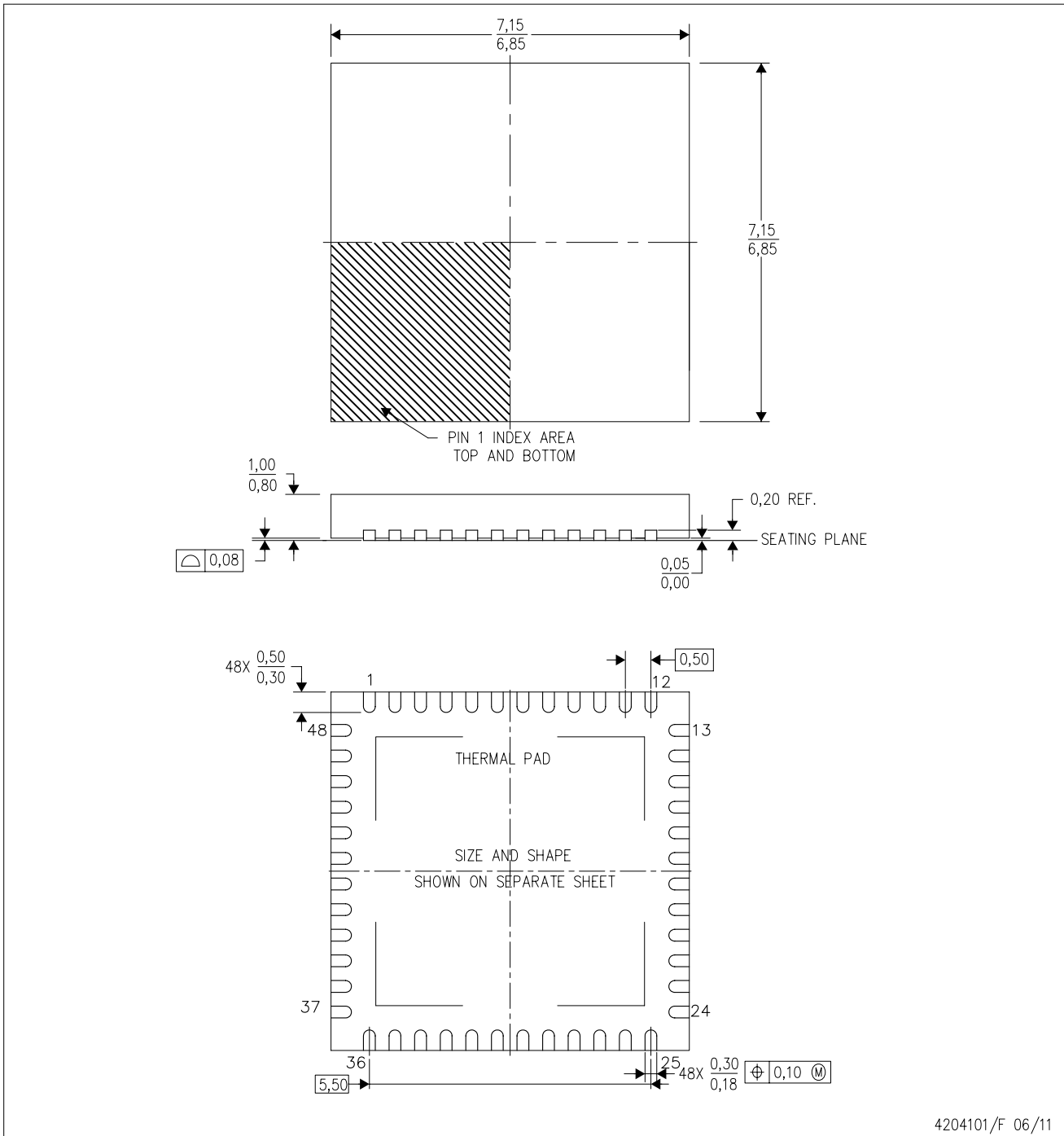
TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|--------------|--------------|-----------------|------|------|-------------|------------|-------------|
| DAC3283IRGZR | VQFN | RGZ | 48 | 2500 | 336.6 | 336.6 | 28.6 |
| DAC3283IRGZT | VQFN | RGZ | 48 | 250 | 336.6 | 336.6 | 28.6 |

RGZ (S-PVQFN-N48)

PLASTIC QUAD FLATPACK NO-LEAD



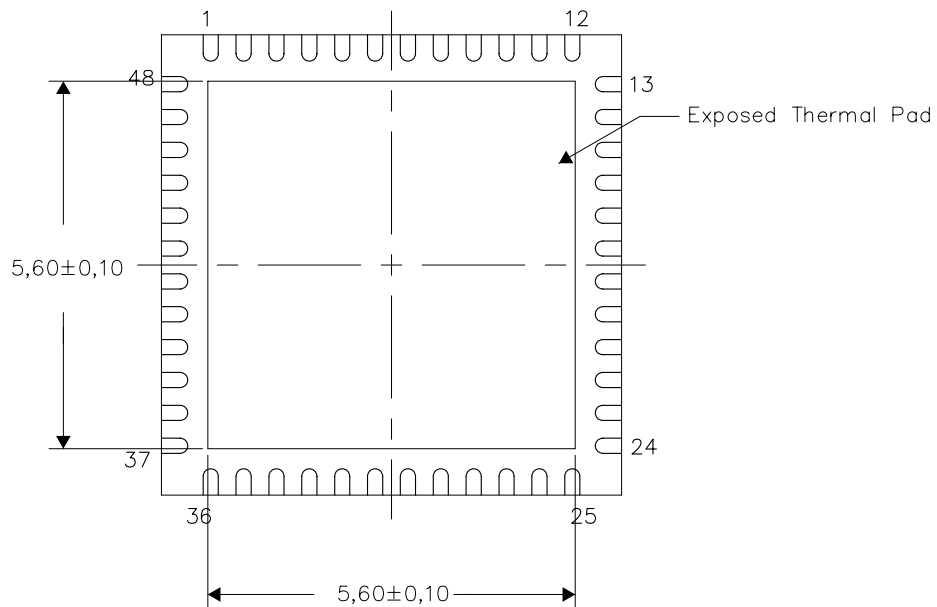
- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. Quad Flatpack, No-leads (QFN) package configuration.
 - D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
 - E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
 - F. Falls within JEDEC MO-220.

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

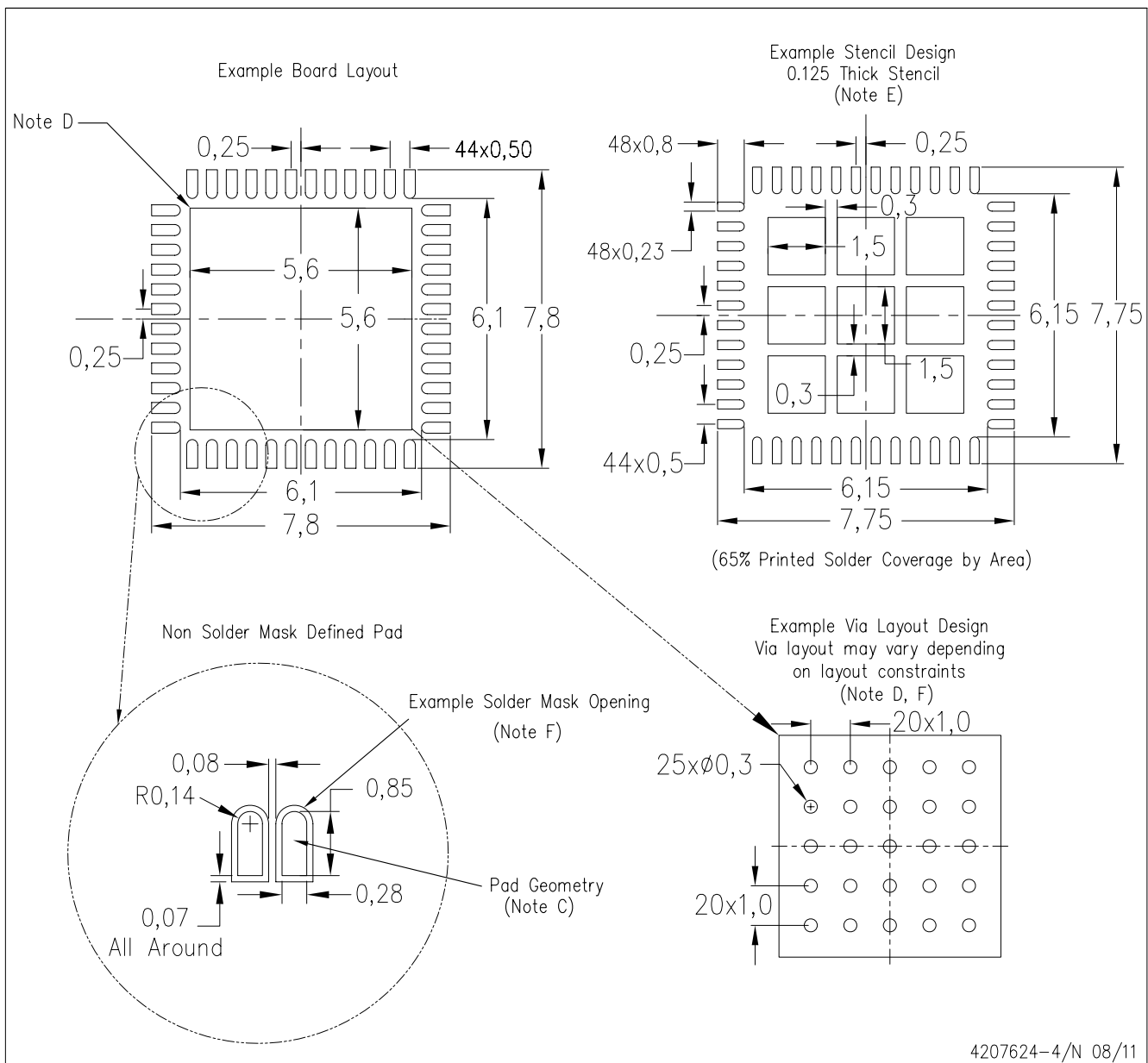
Exposed Thermal Pad Dimensions

4206354-5/R 08/11

NOTE: All linear dimensions are in millimeters

RGZ (S-PVQFN-N48)

PLASTIC QUAD FLATPACK NO-LEAD



- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Publication IPC-7351 is recommended for alternate designs.
 - This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <<http://www.ti.com>>.
 - Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
 - Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

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